

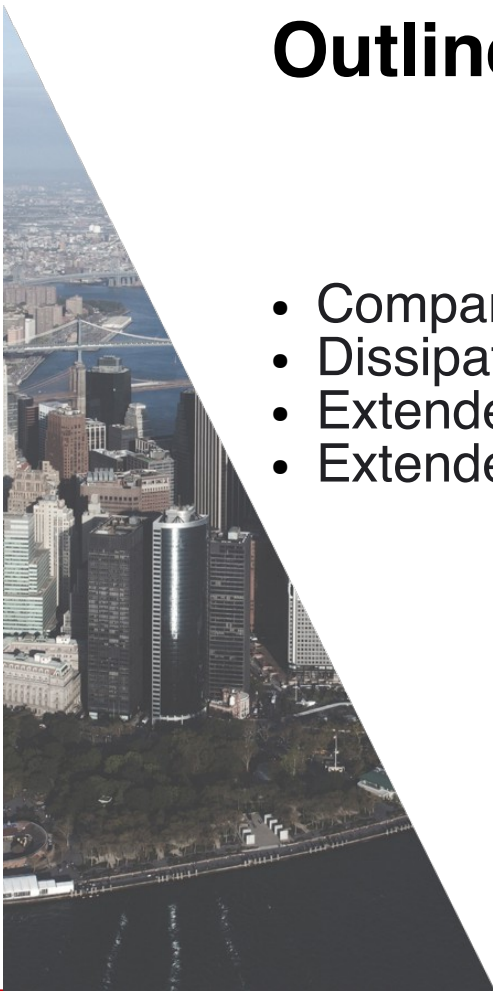


Thermal management of Packaged QCL

A. Muller, S. Blaser, J. Butet, T. Gresch, R. Maulini, N. Villa


Outline

- Company presentation
- Dissipation simulations
- Extended tuning with integrated heater (QC-ET)
- Extended tuning based on Vernier effect (QC-XT)



A photograph of a modern office desk with a laptop, a notebook, and a mug, set against a large window overlooking a city skyline.

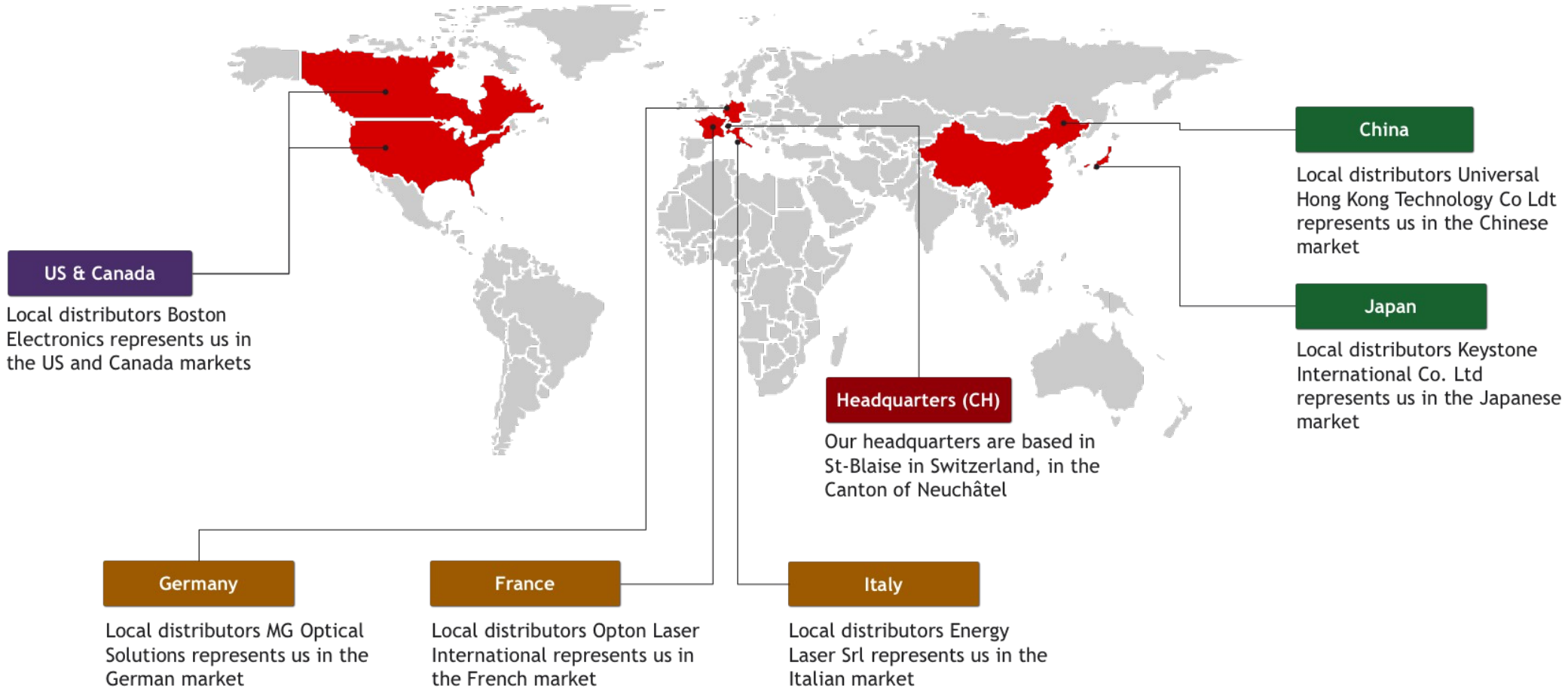
ALPES LASERS
Quantum Cascade Technologies

A large, abstract graphic on the left side of the slide, consisting of a grid of blue and white geometric shapes, possibly representing a crystal lattice or a photonic structure.

Design & production of infrared photonics
First company to produce QCLs (founded 1998)
Located near Neuchâtel (Switzerland)
Innovation driven
High-level team of experts
Strong proprietary know-how
IPR - 12 major patents in QCLs

20 years of global presence

With distributors in DE, FR, IT, US, CA, JP, CN





Alpes product offering

A wide range of photonic solutions

Laser sources

01

Quantum Cascade Lasers

- Pulsed DFB QCL
- Continuous-Wave DFB QCL
- Pulsed FP/Broad Gain QCL
- High Power Pulsed FP QCL
- Custom developments

Interband Cascade Lasers

Diodes Lasers

Pulsed FP THz QCL
(cryogenic)

Electronics

02

Electronic Drivers (Pulsed/CW)

- S-2 Driver
- S-3 Driver
- S-4 Driver

Temperature Controller TC-3

Subcomponents

03

External Cavity Laser kit
Pigtailed components/lasers
Laser/photodetector
assemblies
Custom systems

ALPES LASERS Laser housing options

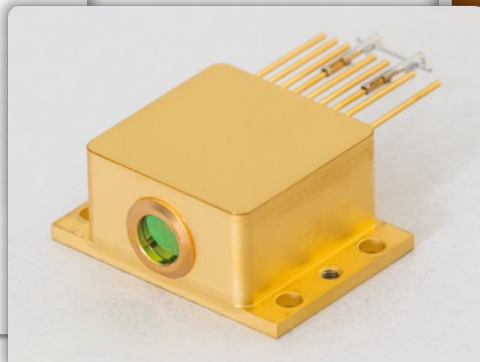
Select the one suitable for your needs



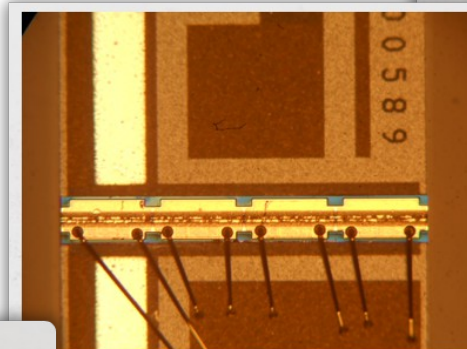
LLH



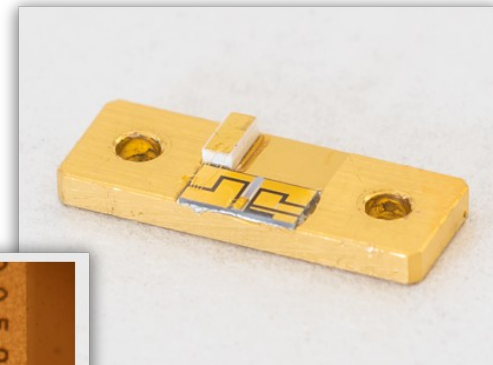
T03



HHL



AlN submount



Cu submount



Bare chip



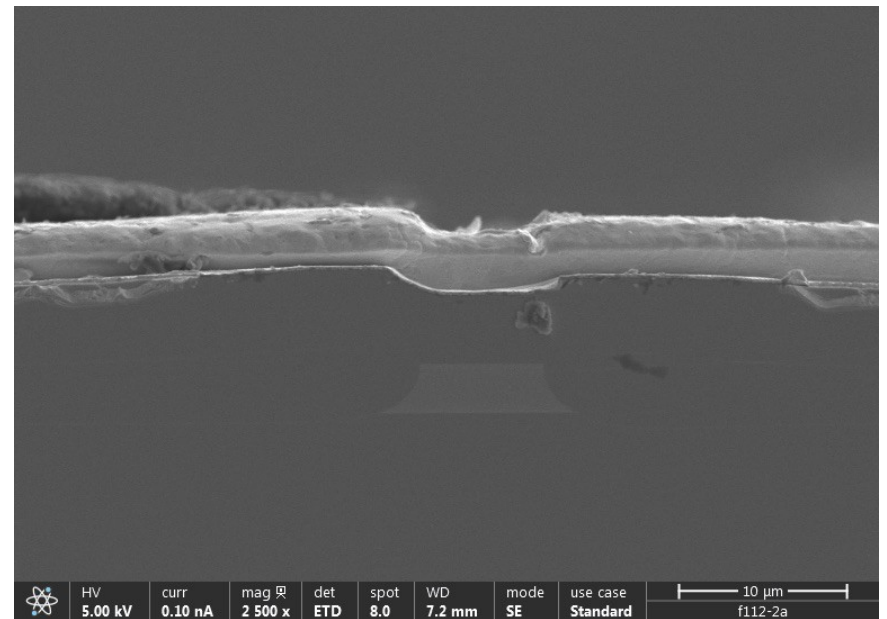
Introduction

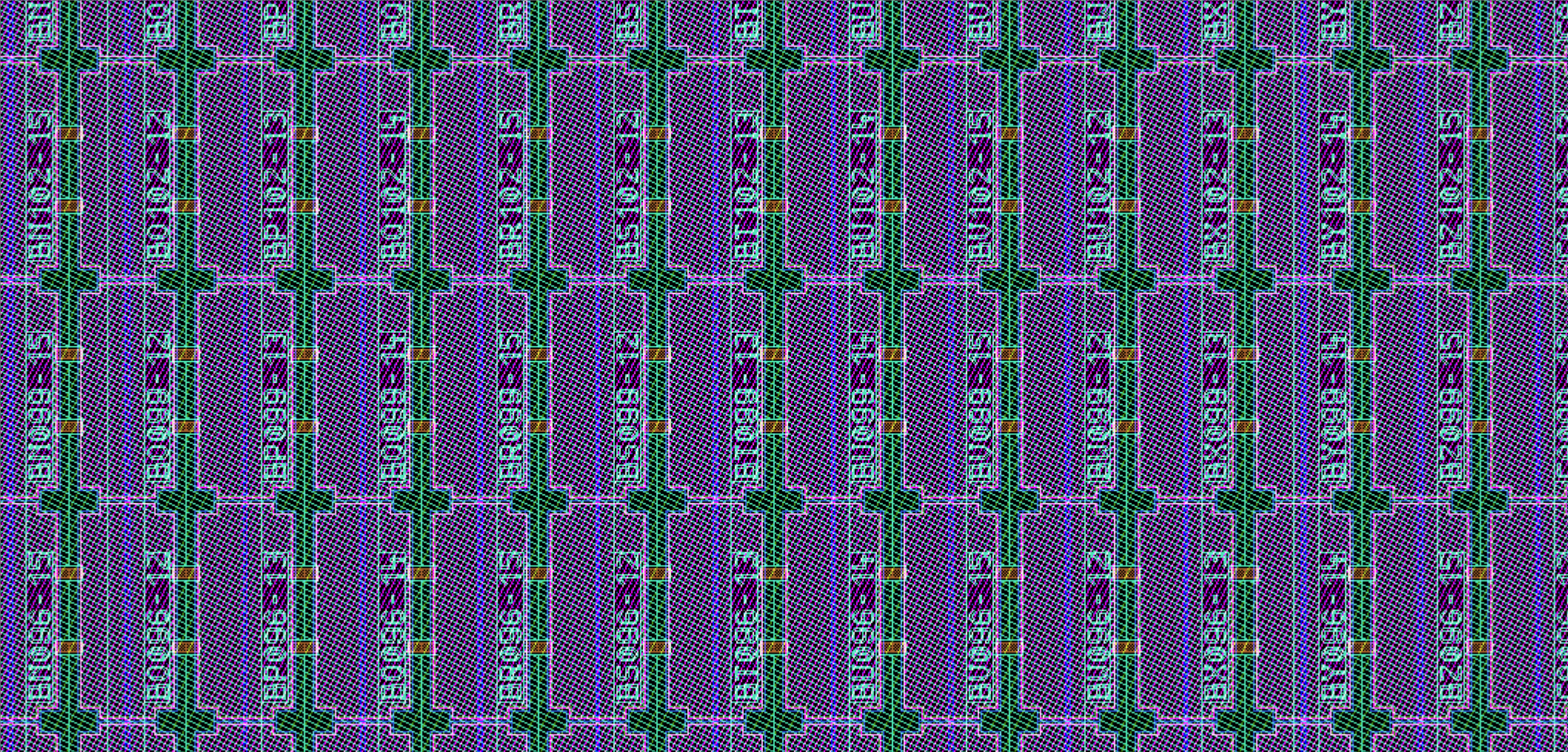
QCL heat dissipation (continuous-wave operation):

- Max voltage: $V_{\max} = 12-15 \text{ V}$
- Max. current density: $J_{\max} = 3-5 \text{ kA/cm}^2$
- Heat dissipation per unit volume: $P_{\text{el}} = 2-5 \times 10^8 \text{ kW/cm}^3$

Active region thermal conductivity:

- Parallel to layers: $k_{\parallel} = 9.0 \text{ W/(mK)}$
- Perpendicular to layers: $k_{\perp} = 2.2 \text{ W/(mK)}$





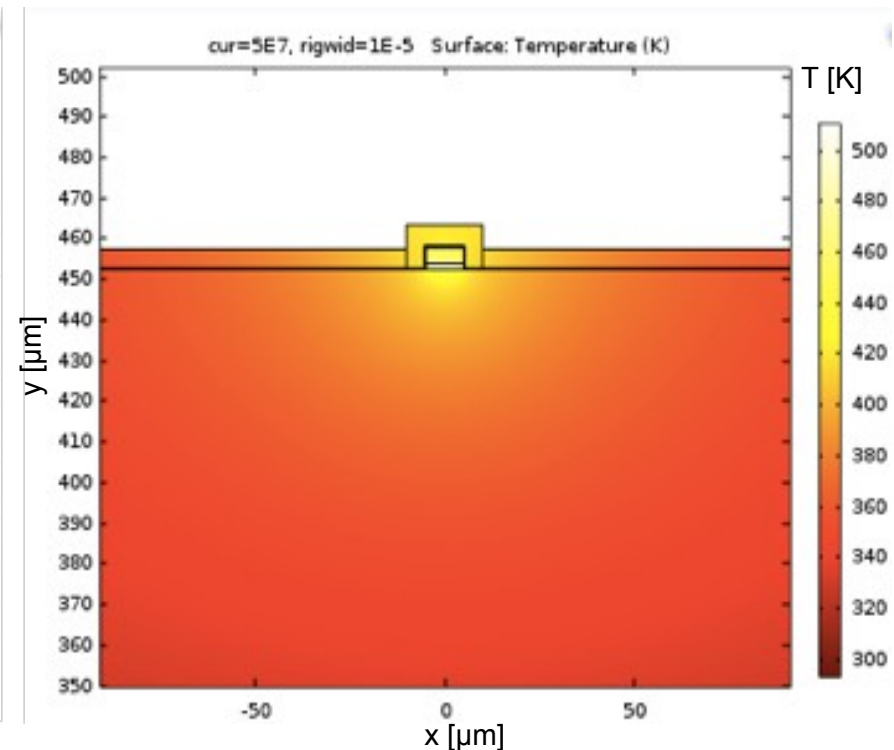
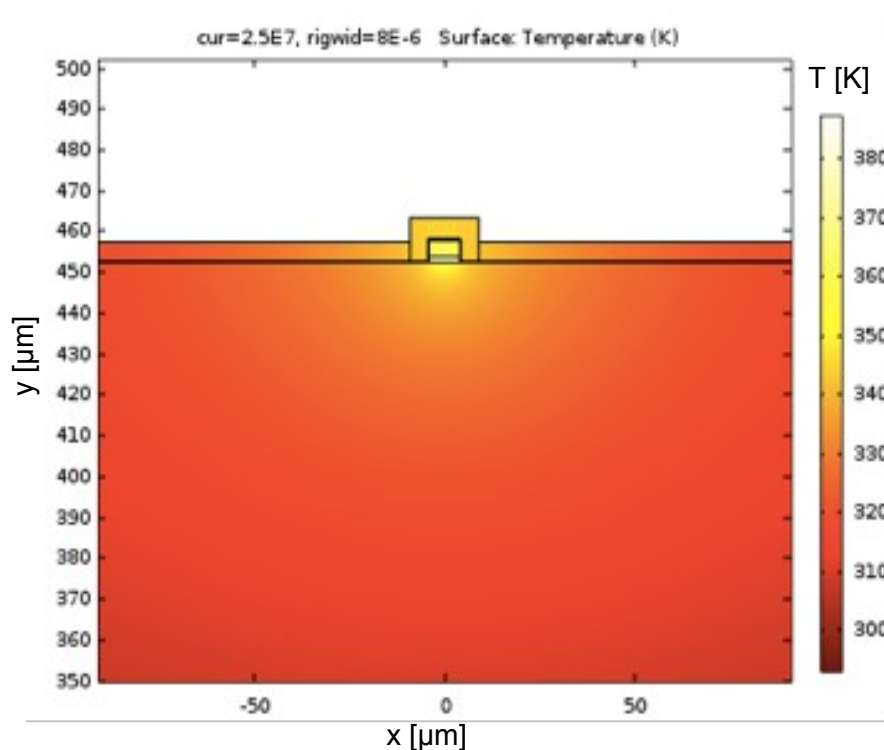
Simulations of various configurations

Material parameters (room temperature)

layer	material	thicknes [um]	Doping [cm-3]	n _r	n _i	El cond [S/m]	thermal cond [W/(m.K)]	density [kg/m-3]	specific heat capacity [J/(kg.K)]
heatsink holder	copper	-	-				385	8900	387
solder	indium	-	-				86	7310	233
submount	AlN	300	-				170	3260	740
solder	AuSn	2.5	-			6e6	57	14700	150
el. plated contact	gold	4	-	12.0742	60.35309	4e7	318	19300	129
top contact	InGaAs	0.2	1e19	0.1777	3.058111		4.6	5500	300
high dop clad	InP	1	8e18	0.322	0.808011	6.9e5	59	4810	310
mid dop clad	InP	4	5e16	3.0315	0.000536		59	4810	310
low dop clad	InP	3	2e16	3.0376	0.000214	2592	59	4810	310
active region (x)	InGaAs/ AlInAs	3.5	-	3.2655	0		9.0	5000	300
active region (y)	InGaAs/ AlInAs	3.5	-	3.2655	0		2.2	5000	300
substrate	InP	150	1e16	3.0396	0.0001		59	4810	310
regrowth	InP	-	0	3.0416	0	1e-15	59	4810	310
isolation layer	SiO	0.3	-				1.25	3180	160
isolation layer	Si3N4	0.3					25.5		

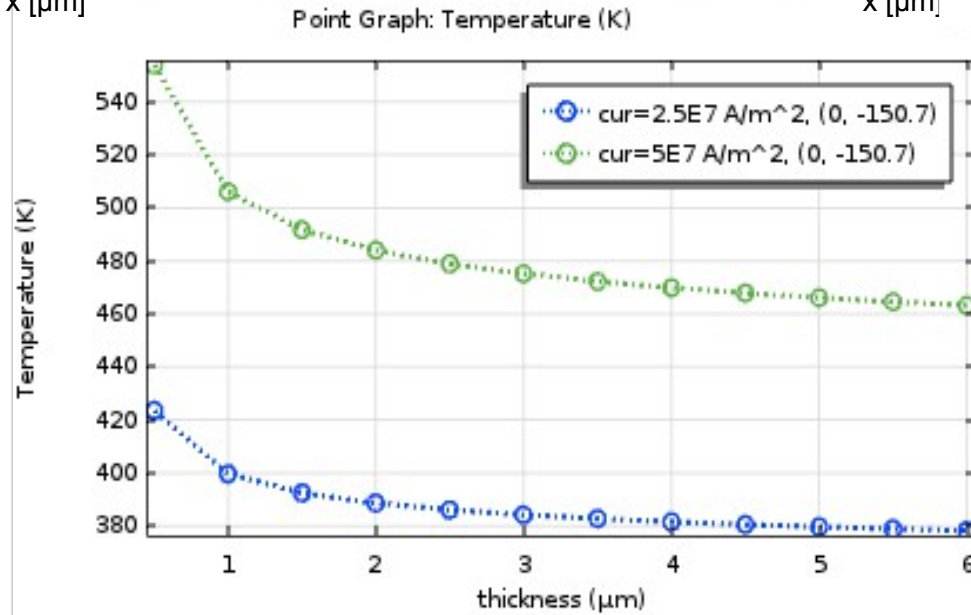
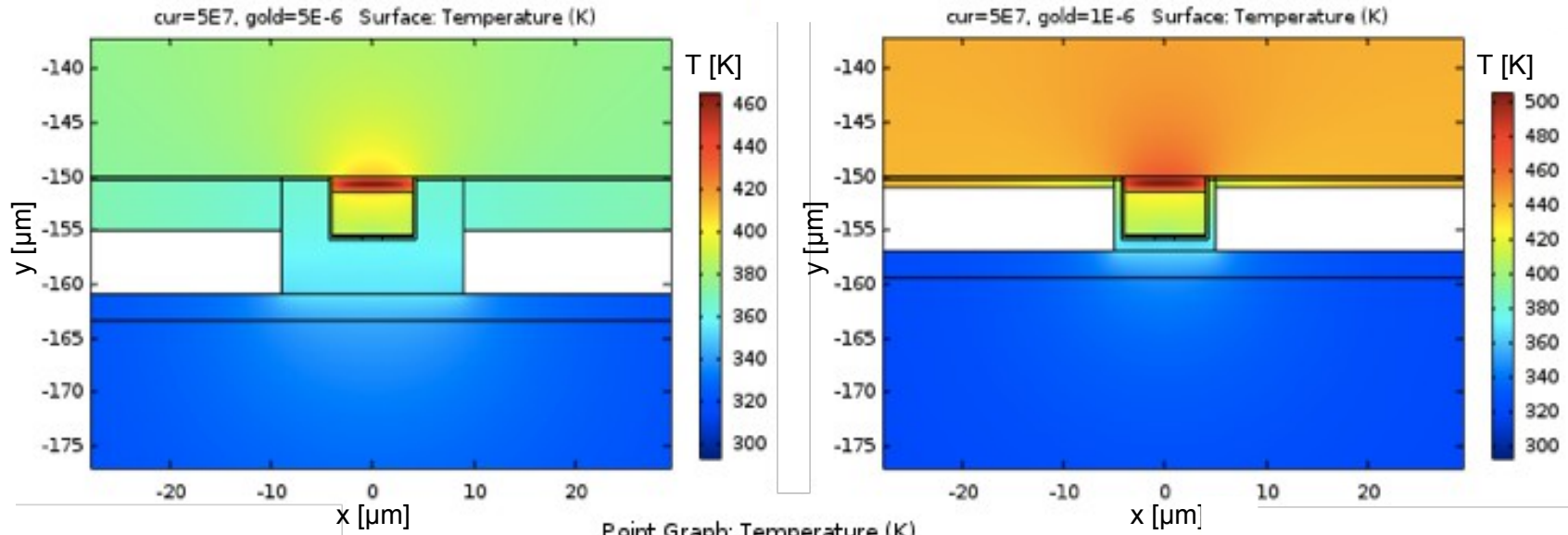
Basic configuration:

- Ridge waveguide (RWG) processing
- Epitaxial-side-up (epi-up) bonding



Current density	w=8um	w=10um
J=2.5 kA/cm ²	390 K	404 K
J=5 kA/cm ²	485 K	513 K

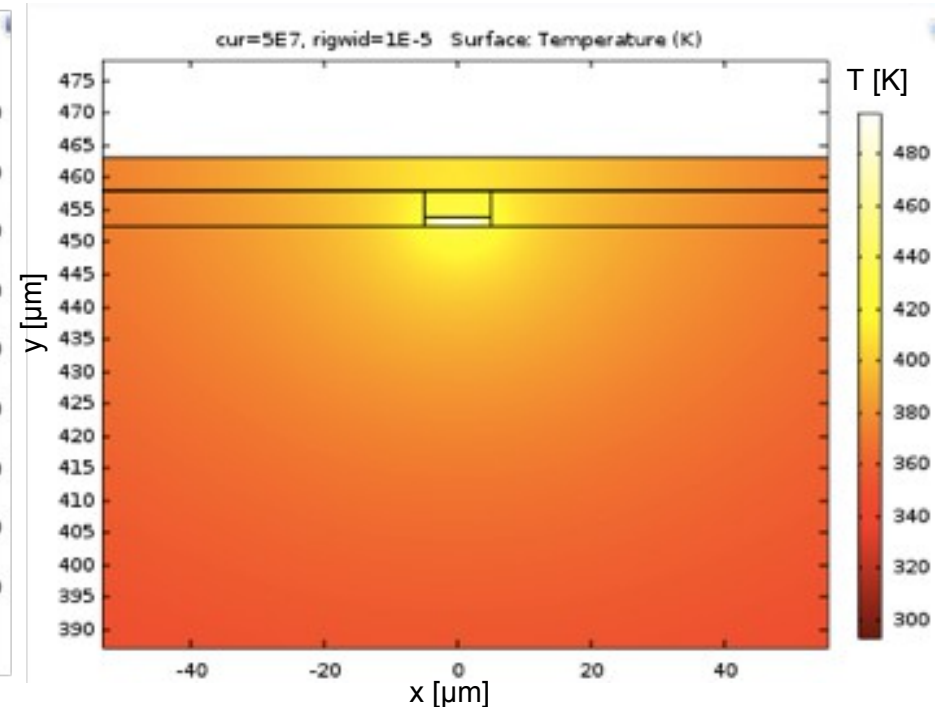
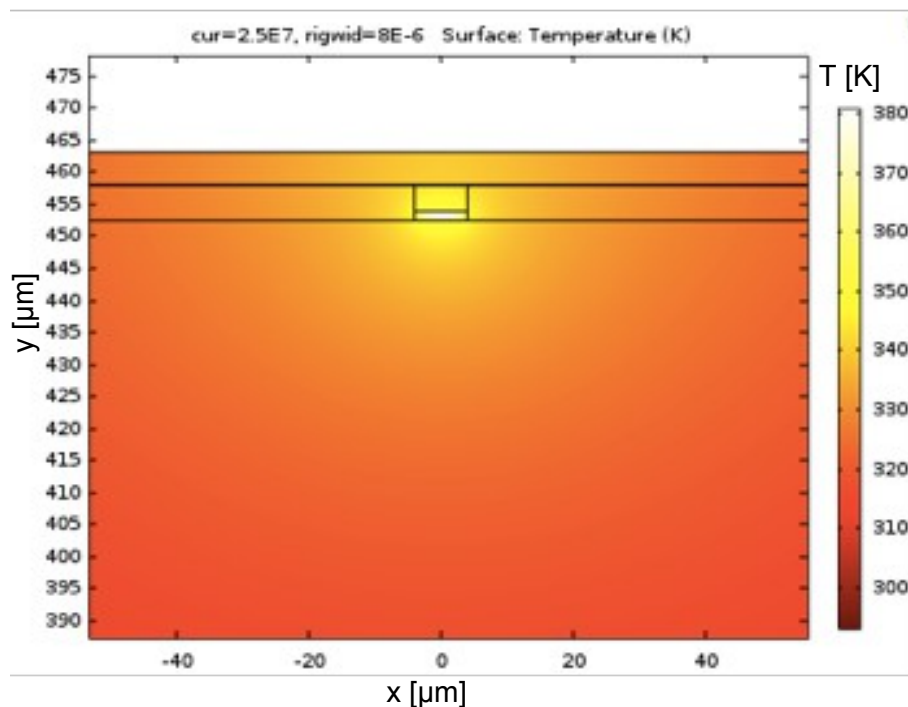
Impact of electroplated gold thickness



- RWG processing
- $w = 10 \mu m$
- Epi-down bonding

Intermediate configuration:

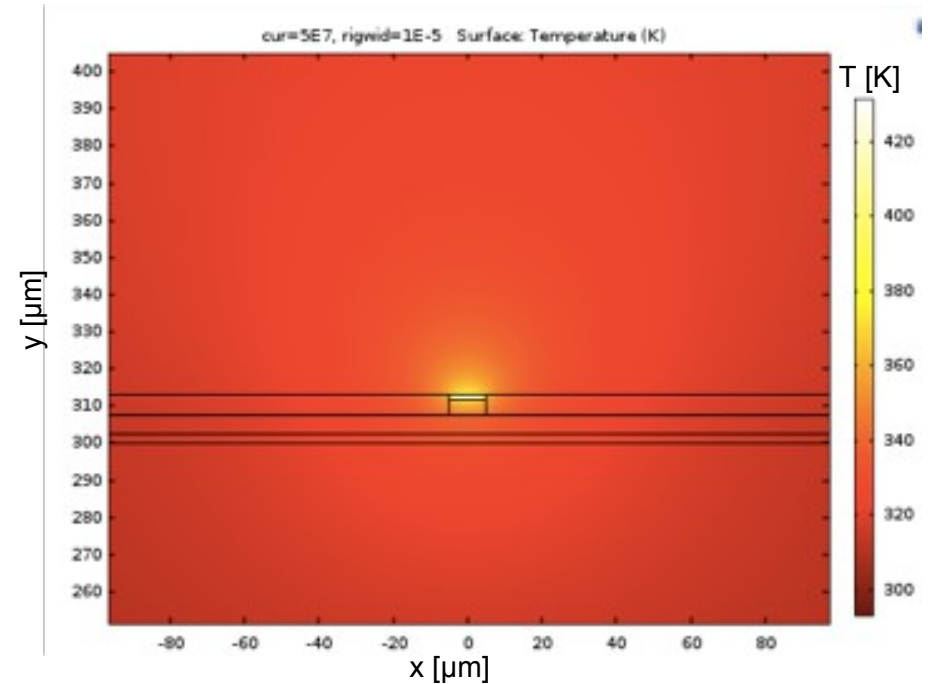
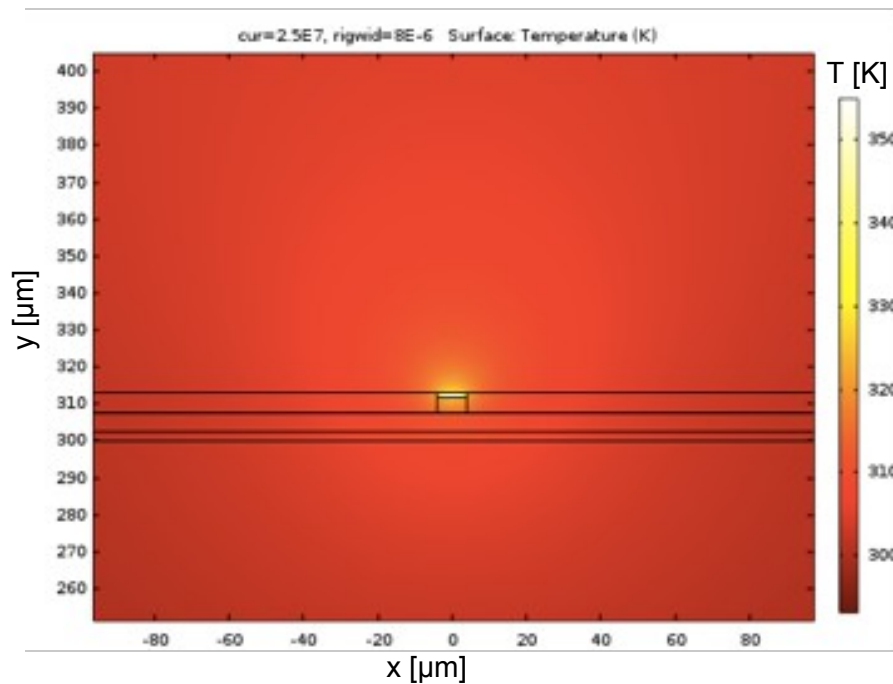
- Buried heterostructure (BH) processing
- Epi-up bonding



Current density	w=8um	w=10um
J=2.5 kA/cm ²	380 K	395 K
J=5 kA/cm ²	470 K	496 K

Optimized configuration:

- BH processing
- Epi-down bonding



Current density	w=8um	w=10um
J=2.5 kA/cm ²	354 K	363 K
J=5 kA/cm ²	415 K	430 K

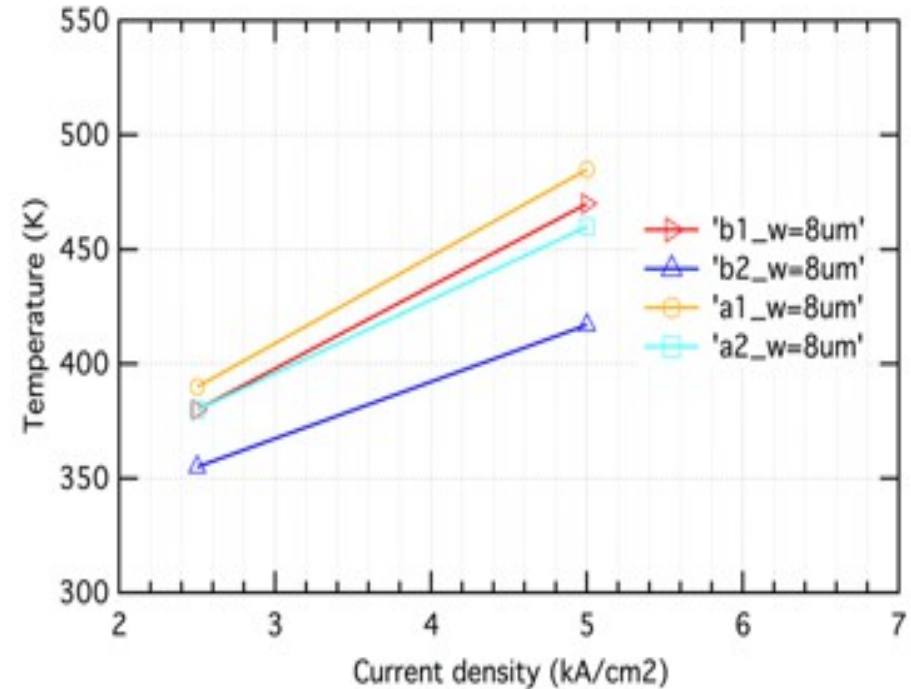
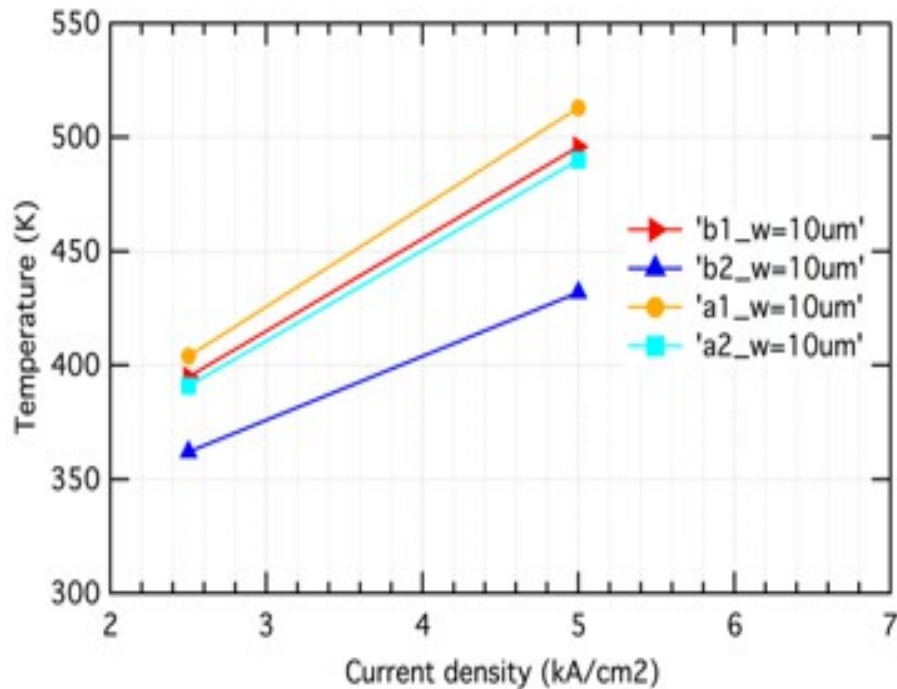
Comparison of various configuration

a1: RWG, epi-up

b1: BH, epi-up

a2: RWG, epi-down

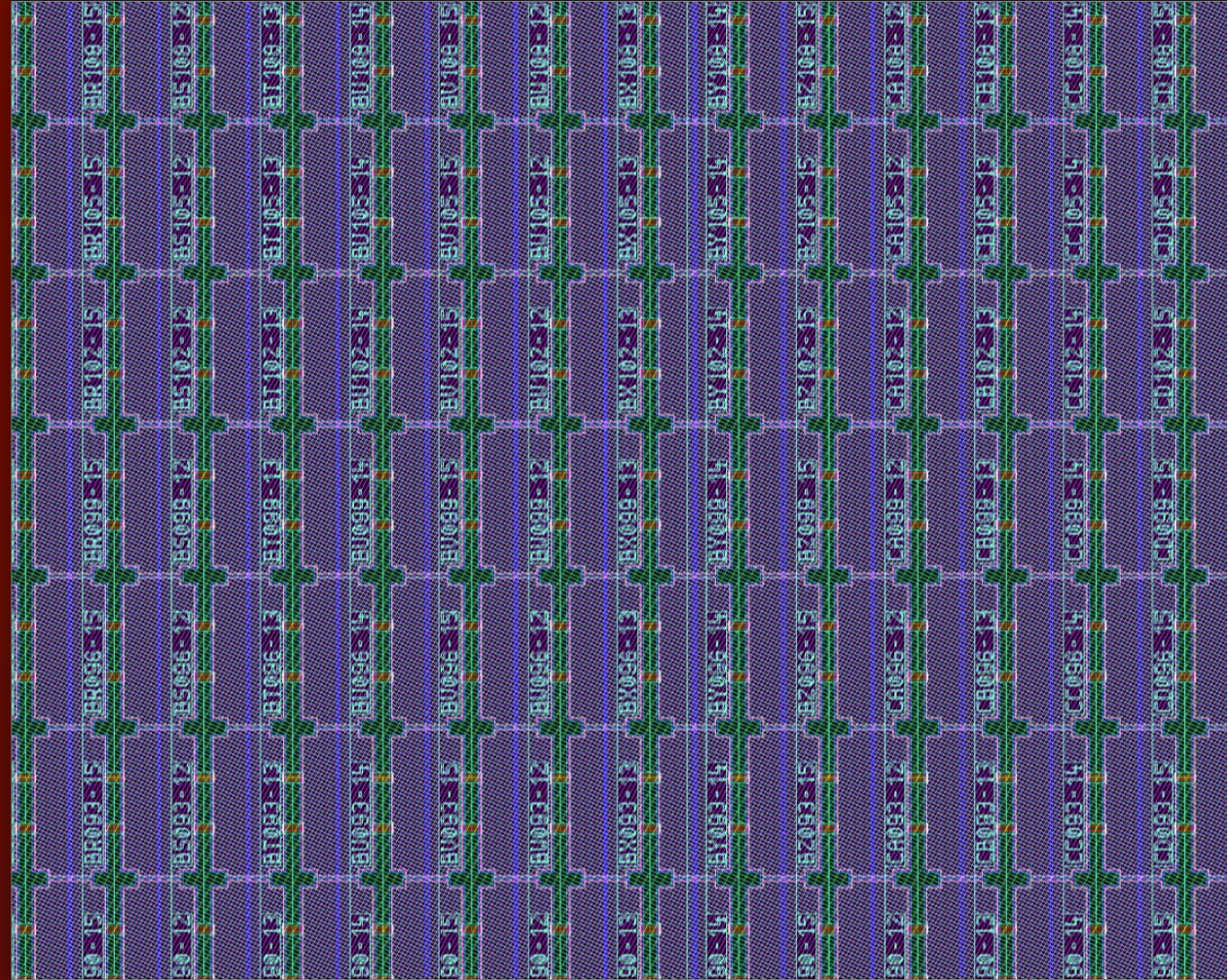
b2: BH, epi-down



- Worse heat dissipation: RWG, epi-up
- BH epi-up and RWG epi-down have similar performance
- Significant improvement in BH epi-down configuration

High power QCLs

HP-QCL



High power QCLs

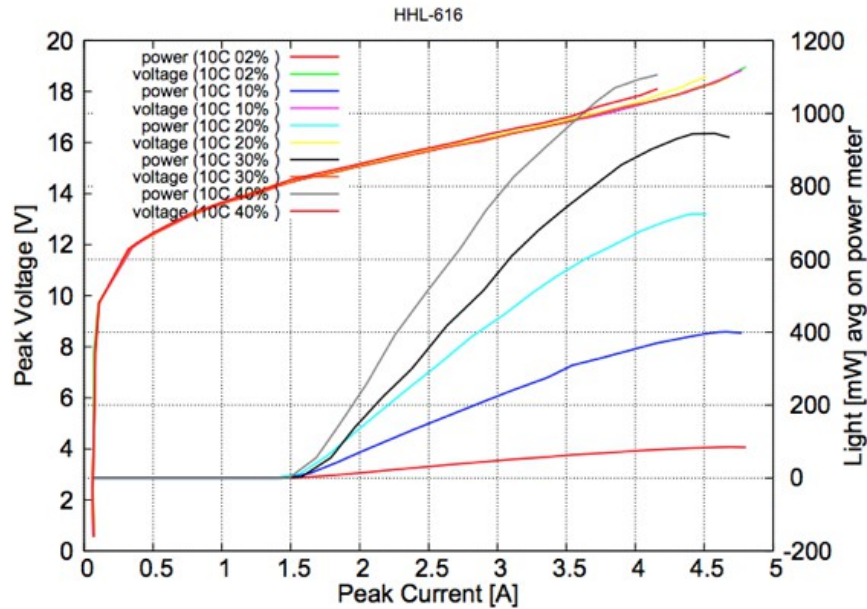
Core technical device characteristics

- High power QCL activity started 5 years ago
- Watt-level multimode devices at $\lambda = 4.0, 4.6, 4.9, 9.0,$ and $9.7 \mu\text{m}$
- Demonstrated 1 W narrow-band ($< 1 \text{ cm}^{-1}$) devices at $4.7 \mu\text{m}$
- Developed ruggedized packaging for defense application
 - Excellent beam pointing precision and stability
 - Sustain shocks, vibrations, extreme ambient and storage temperatures
- Fully packaged collimated QCLs currently available:
 - 1.5 W at $\lambda = 4.55, 4.65,$ and $4.90 \mu\text{m}$
 - 1.0 W at $\lambda = 3.95 \mu\text{m}$
 - 1.0 W at $\lambda = 9.05, 9.70 \mu\text{m}$
- OEM driver

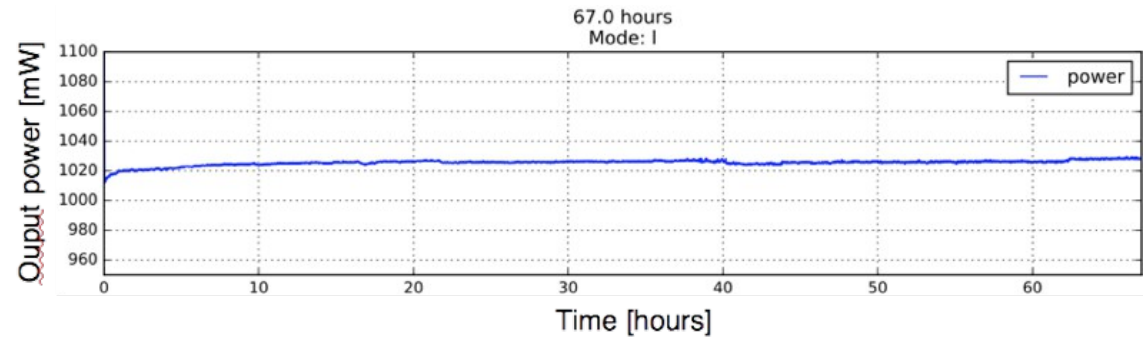
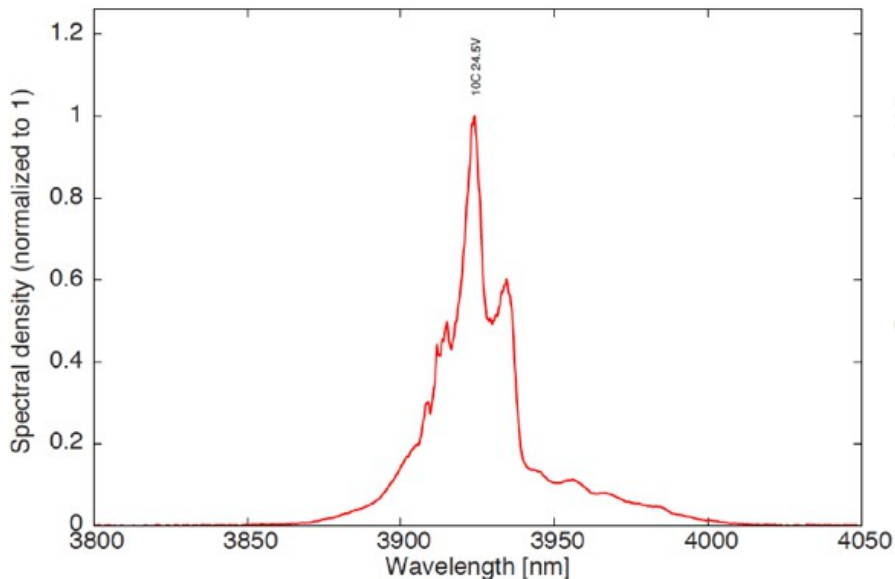


High power QCLs

4.0 μm QCL – package level performance

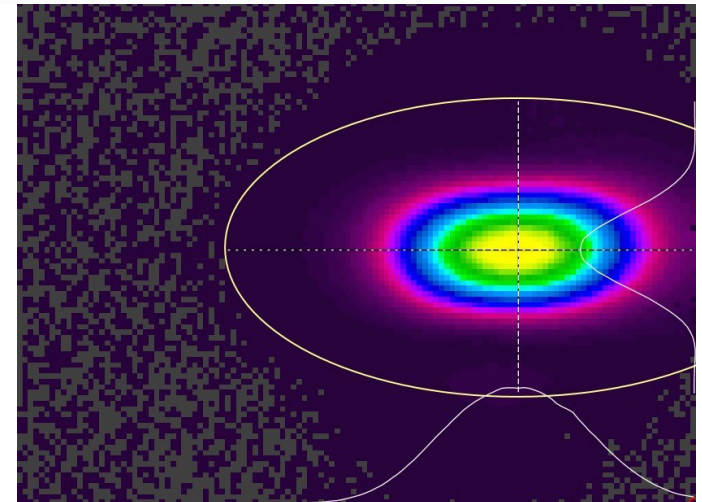
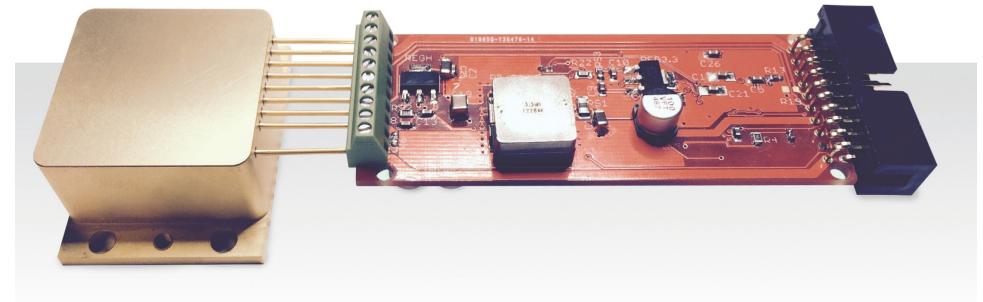
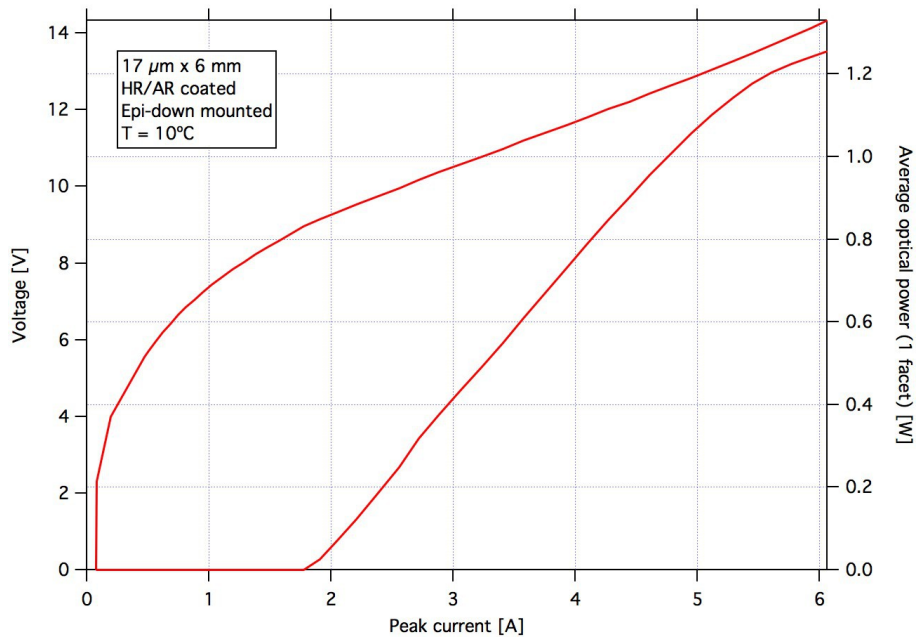


- $T = 10^\circ\text{C}$
- >1 W average power at $\lambda = 3.925 \mu\text{m}$
- Wall-plug efficiency = 5% at 10°C
- All units are burned in at full power before delivery



High power QCLs

9.7 μm QCL – package level performance



- $\lambda = 9.7 \mu\text{m}$
- Average power: 1.25 W at 40% duty-cycle, T = 10°C
- Beam divergence (full angle at 0.8 W): 7.4 x 3.7 mrad
- High beam quality

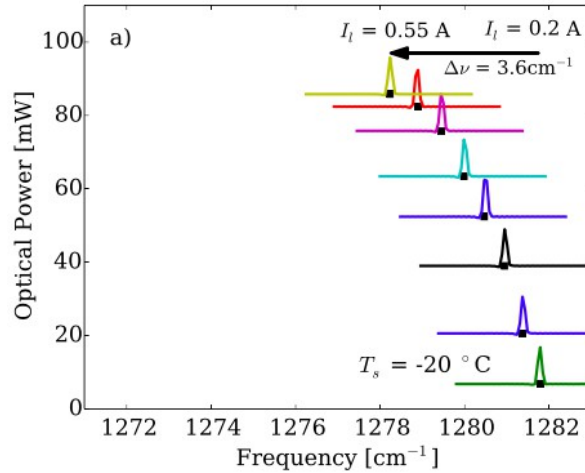
Integrated heater

QC-ET

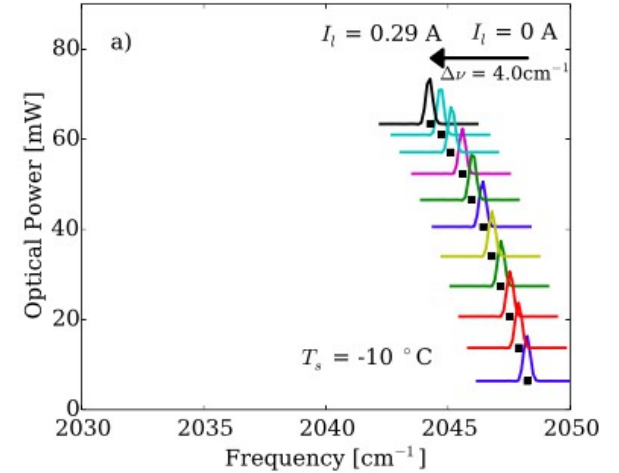
QCL Temperature tuning

Tuning with
laser current

7.8 μm



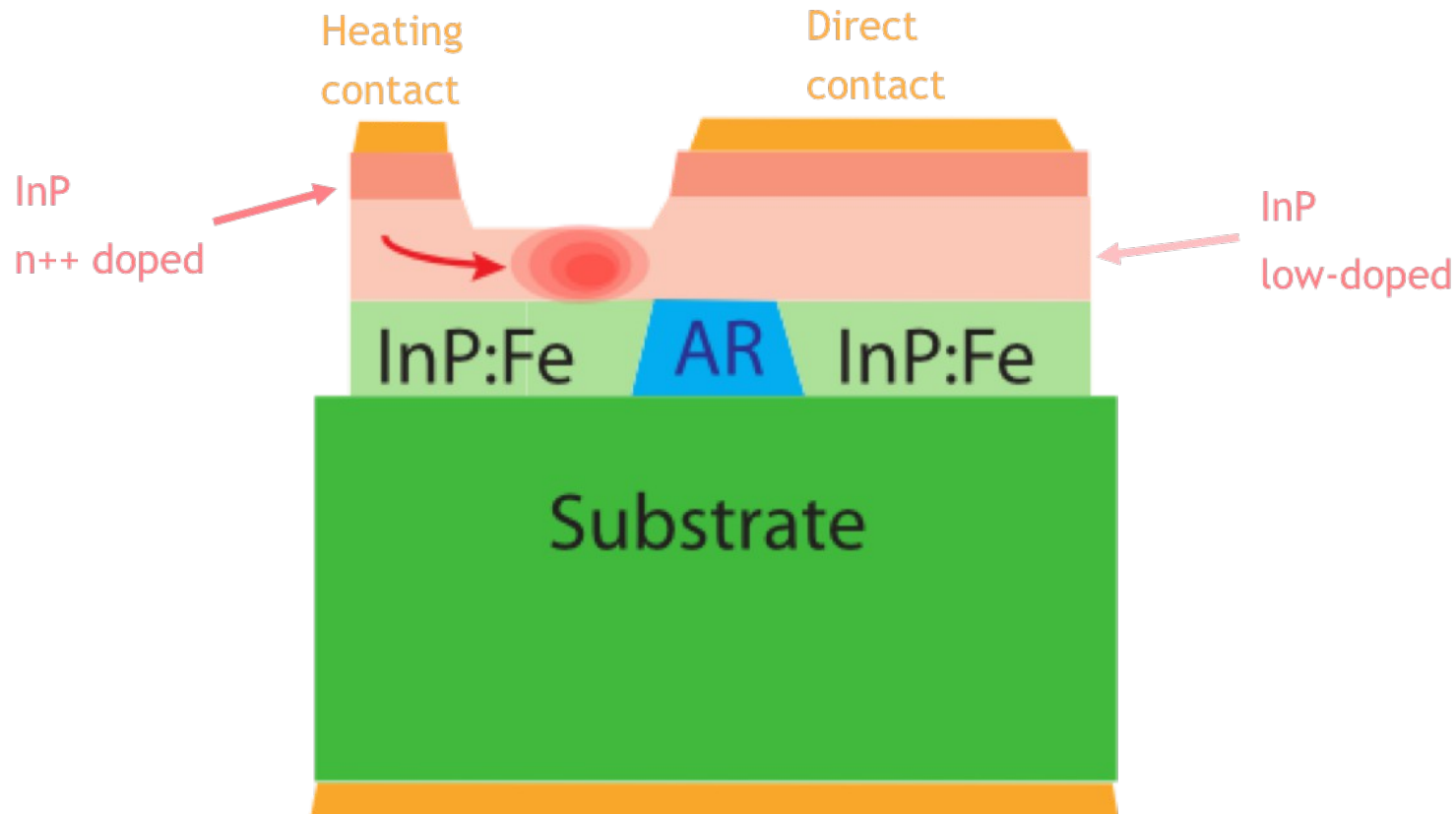
4.9 μm



Integrated heater

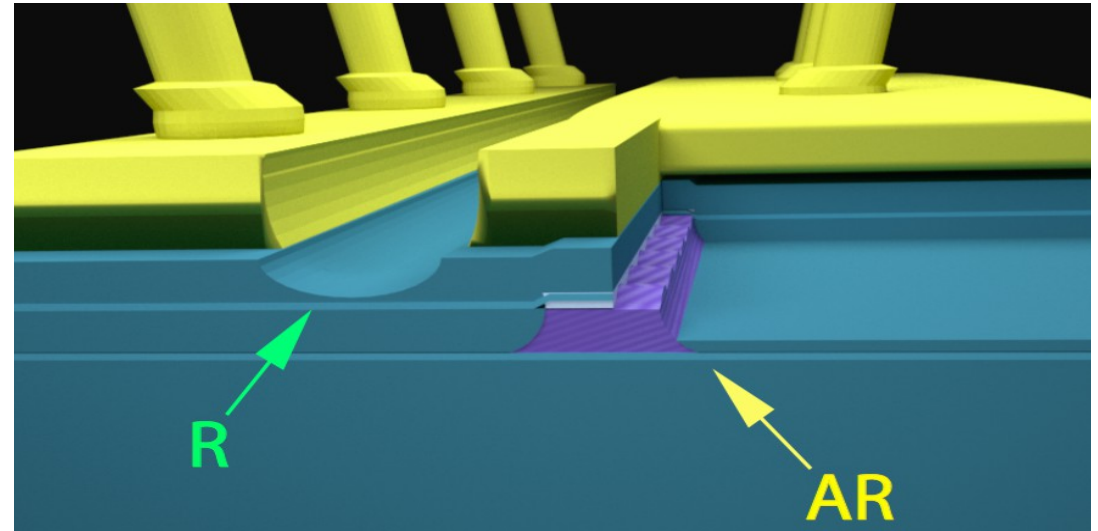
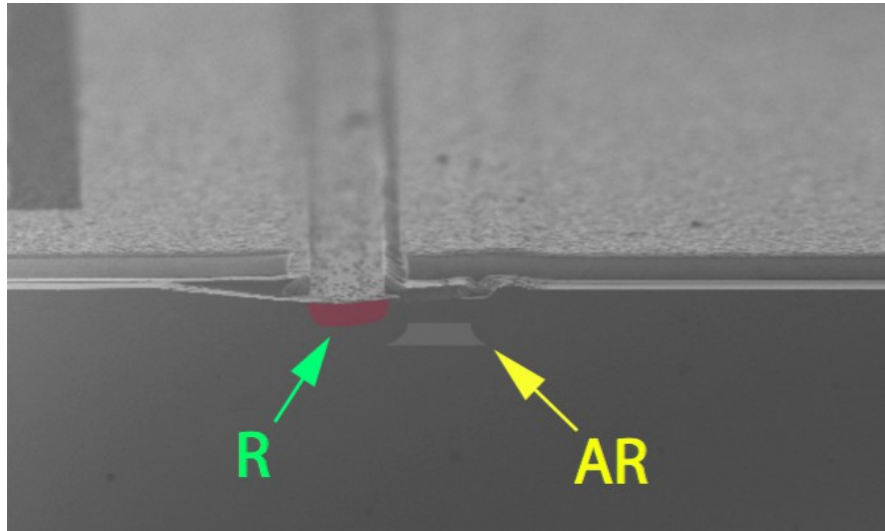
Core technical device characteristics

- New process developed
- Extended top contact for integrated circuiting



Integrated heater

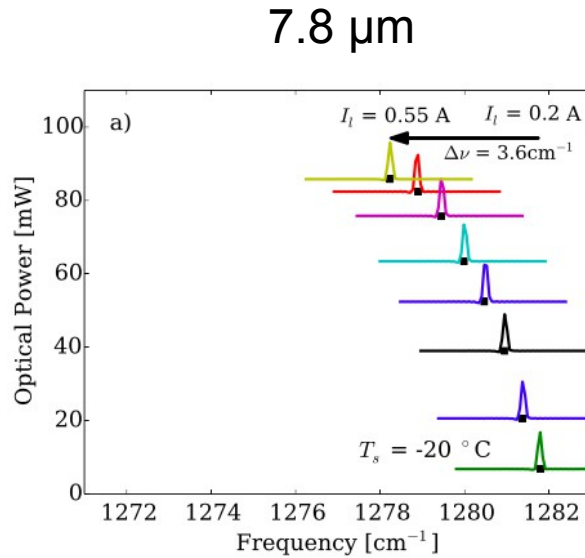
Core technical device characteristics



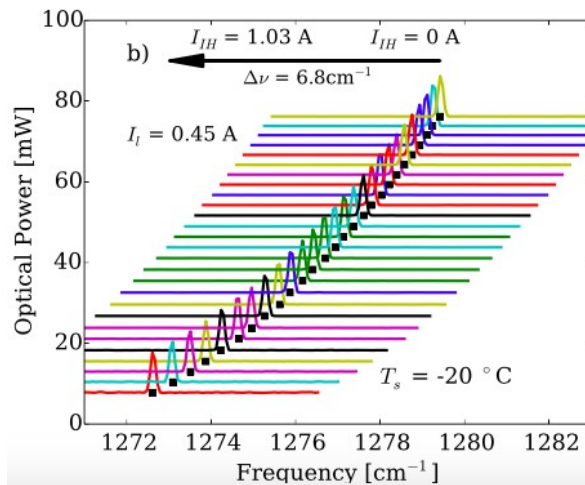
- Resistive heater close to the laser ($<10 \mu\text{m}$)
 - Fast modulation
 - High tuning efficiency (cm^{-1}/W)
- Independent power and wavelength controls

Integrated heater

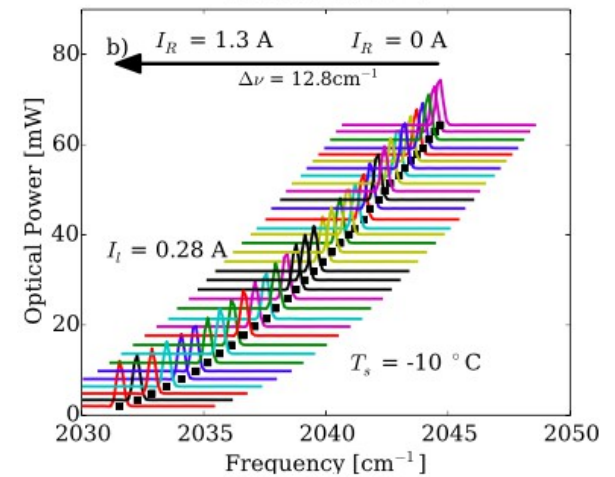
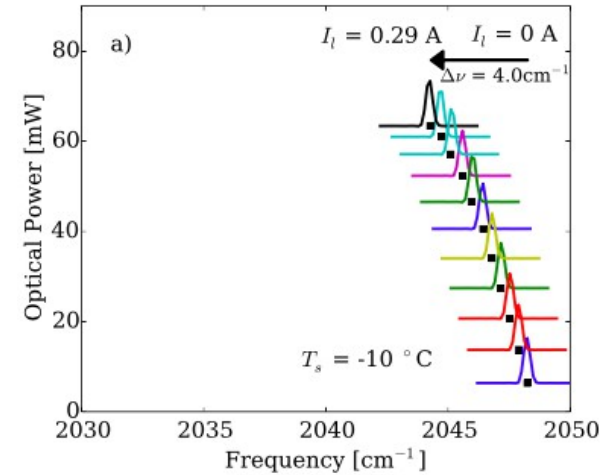
Tuning with
laser current



Tuning with
integrated heater



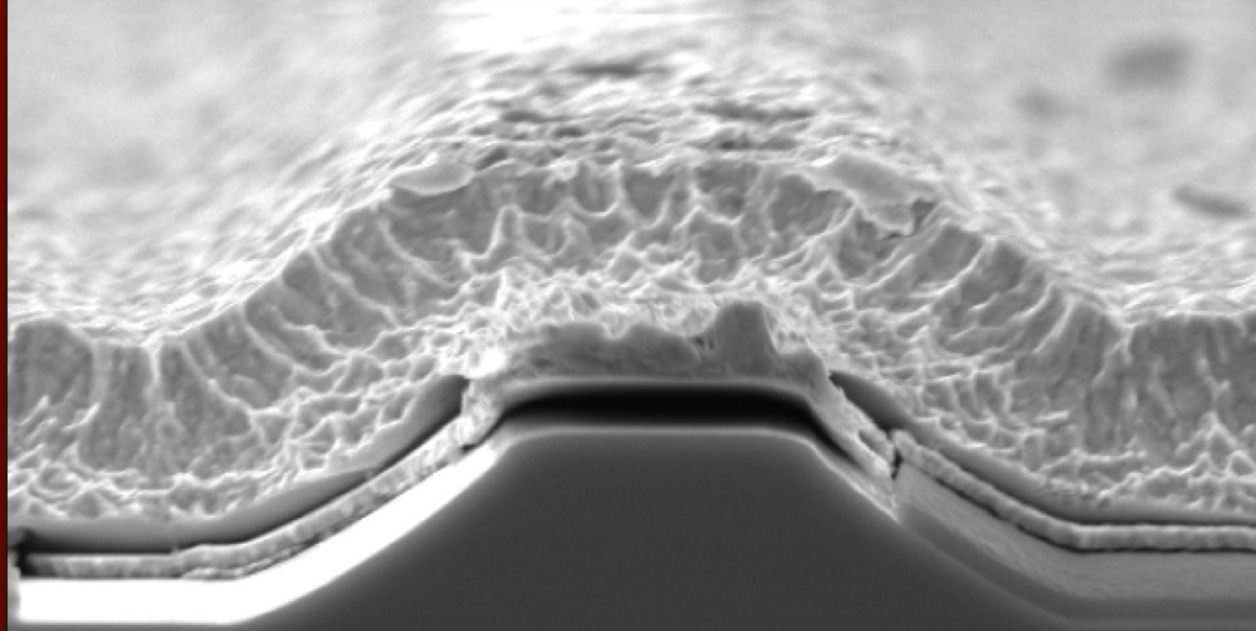
4.9 μm



2-3 times increase in tuning range at constant heatsink temperature

QCLs based on Vernier effect

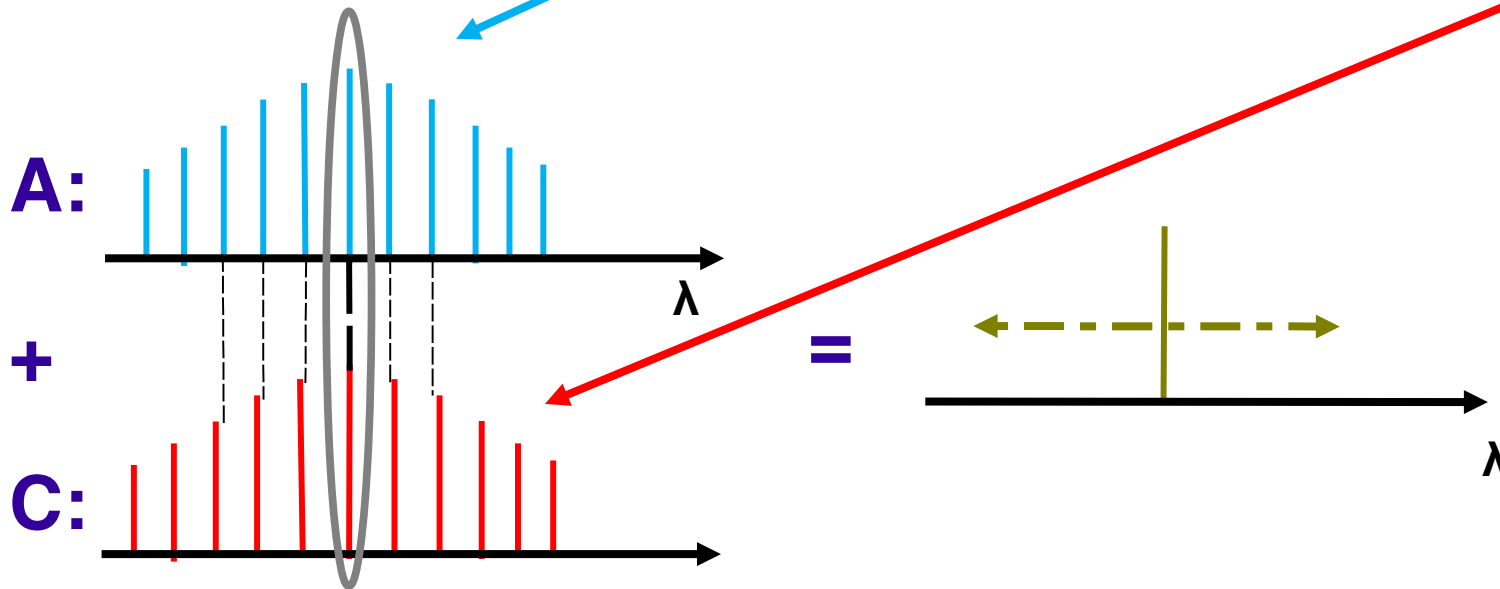
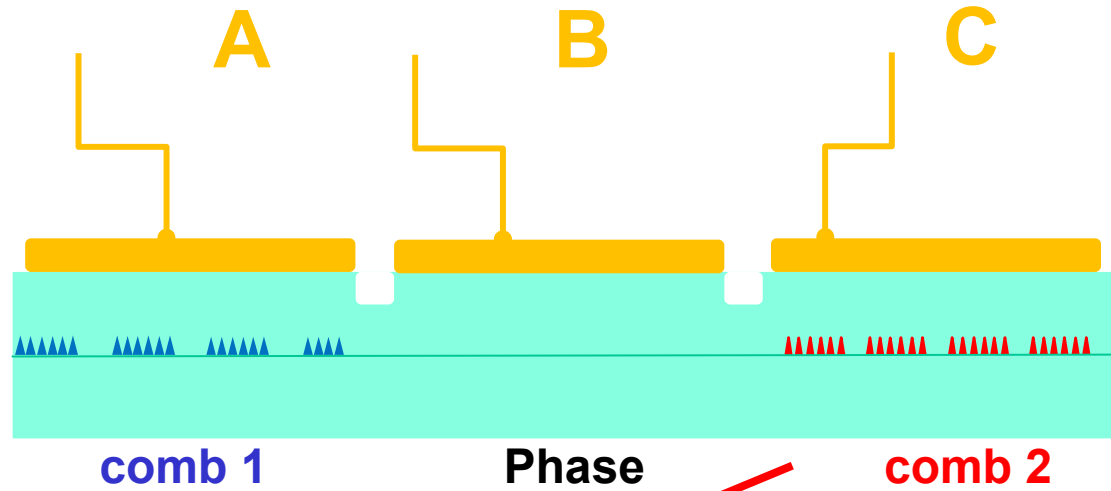
QC-XT



QCLs based on Vernier effect

Core technical device characteristics

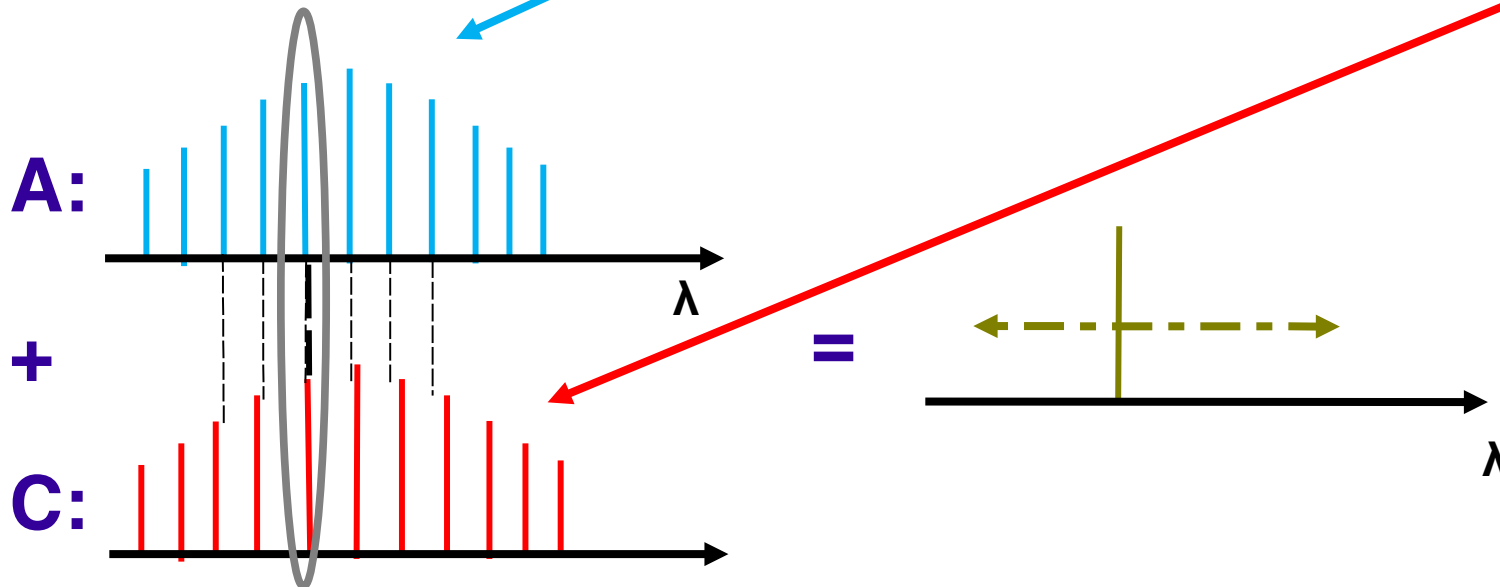
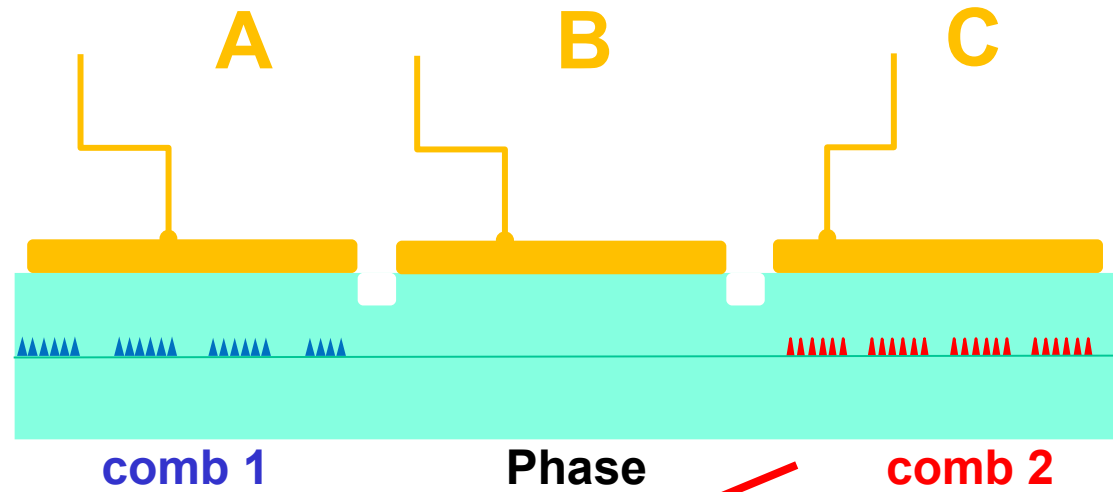
Sampled gratings for comb generation
Wide single chip tuning ($>100 \text{ cm}^{-1}$)



QCLs based on Vernier effect

Core technical device characteristics

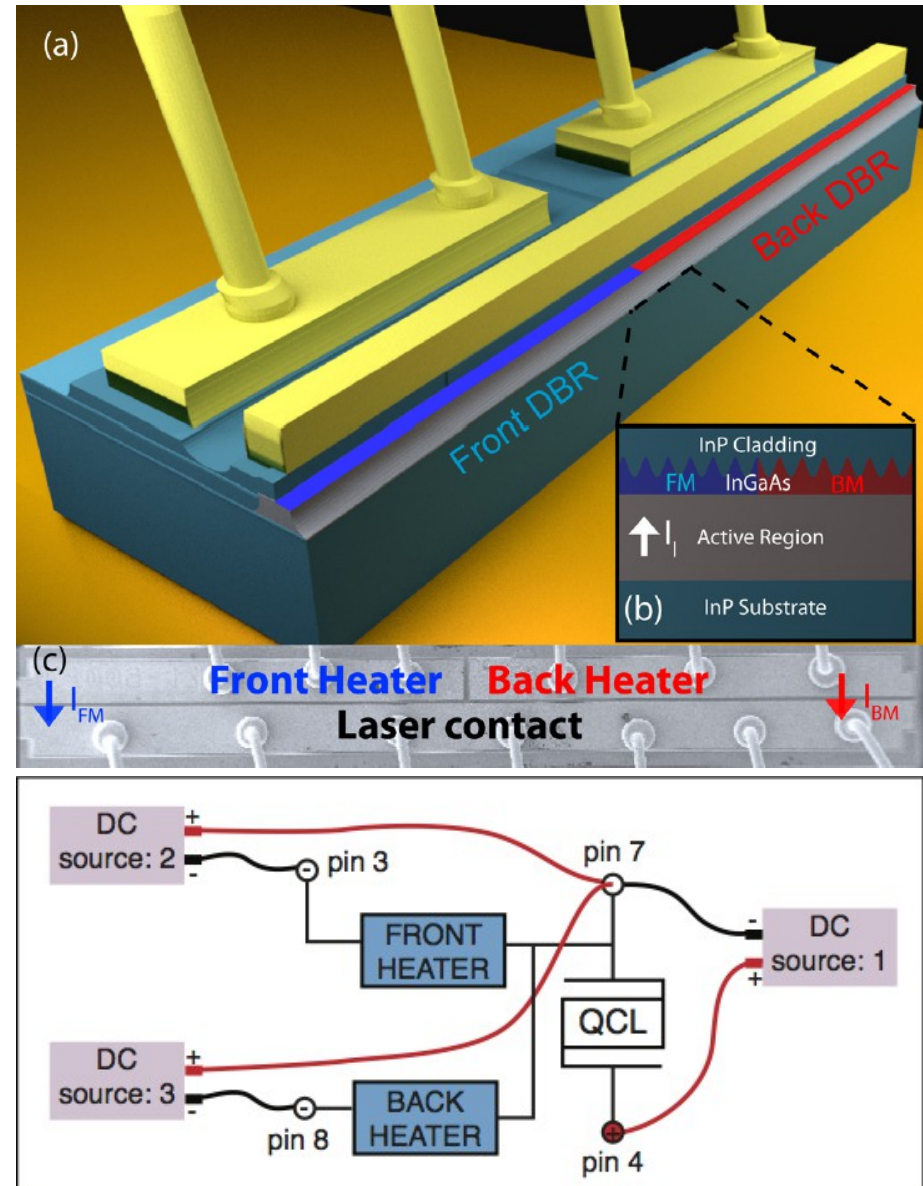
Sampled gratings for comb generation
Wide single chip tuning ($>100 \text{ cm}^{-1}$)



QCLs based on Vernier effect

Core technical device characteristics

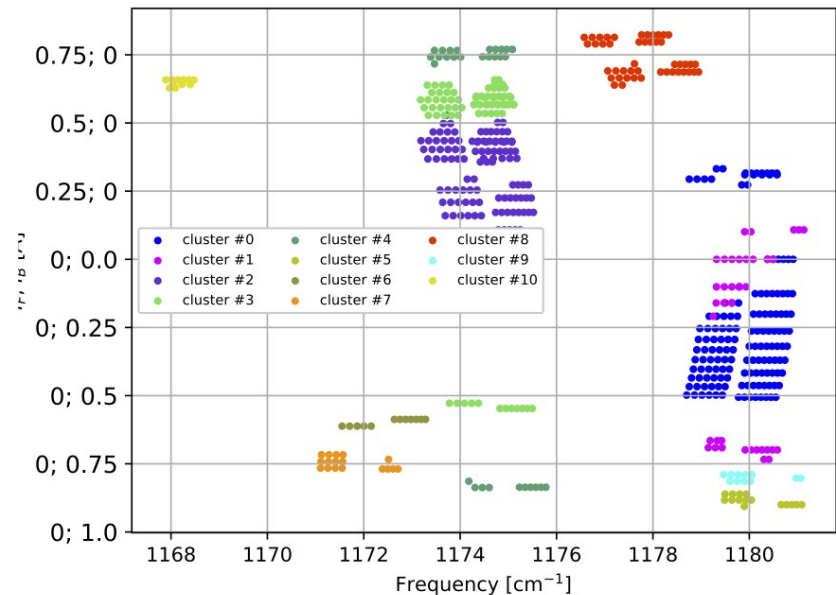
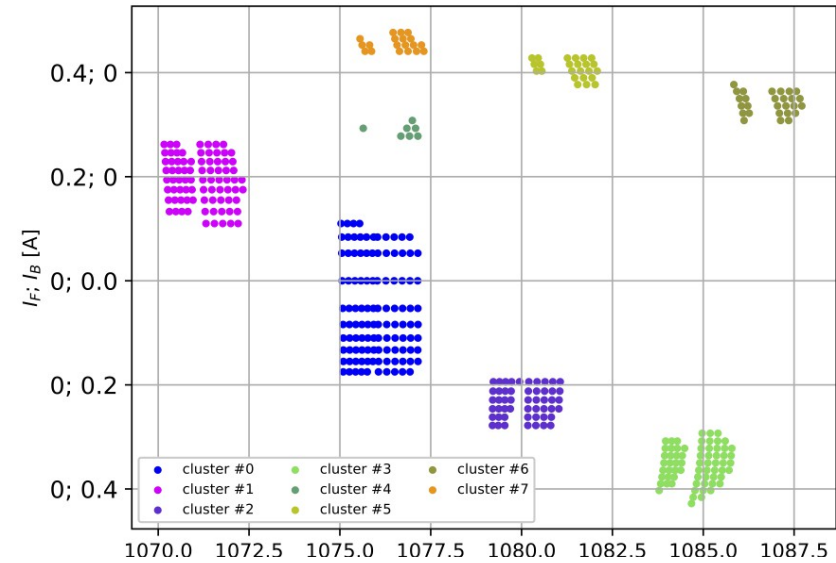
- QC-XT Laser Sources are controlled by three independent current inputs.
- Two inputs control the front and back mirrors of the cavity (I_F and I_B). The laser itself is driven by the laser current I_L and behaves as a normal DFB laser with the available range modified by the values of I_F and I_B .
- Linewidth ~ 1 MHz like DFB lasers.



QC-XT first generation

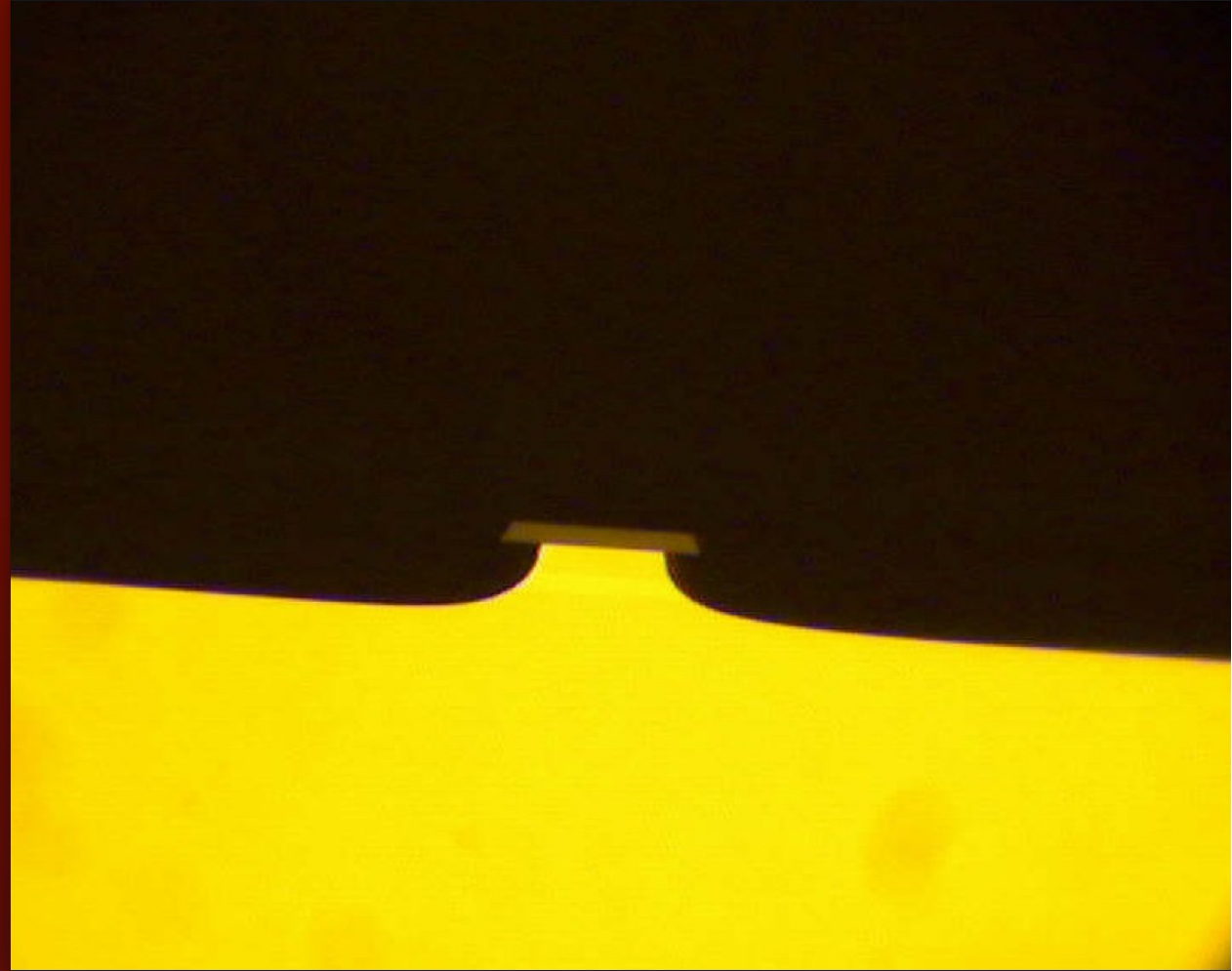
Laser performances

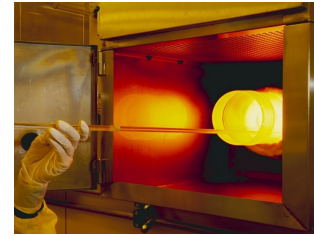
- Maps of single-mode region with continuous tuning zones.
- The laser can jump to any point within the map within < 1 ms.
- Each mode is defined by a triplet (doublet) of input currents at fixed temperature.
- Devices with large number of clusters (up to 9) demonstrated (R & D).
- However:
 - fabrication yield is an issue due to random phase of the cleaved facets
 - designed vs real clusters difficult to correlate
 - constant clusters gaps (SG)



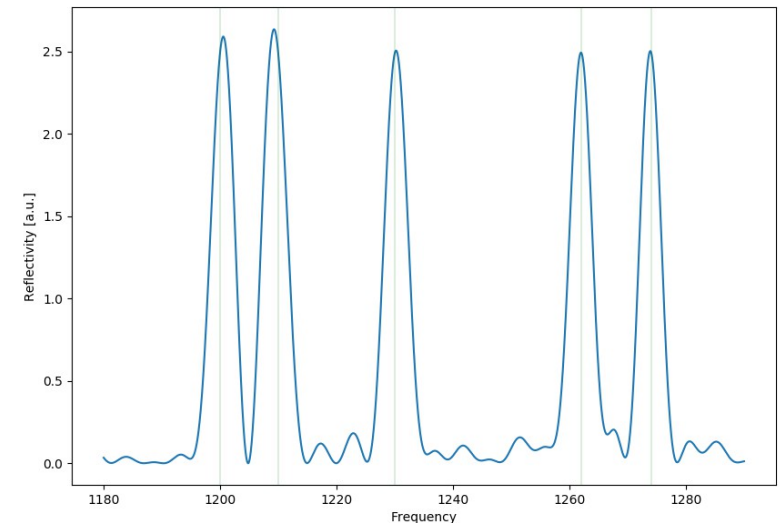
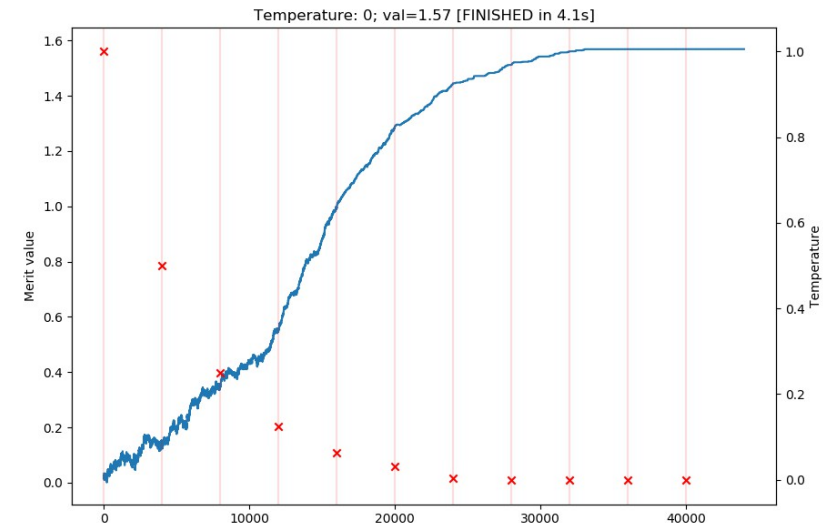
2nd generation of QC-XT

QC-XT

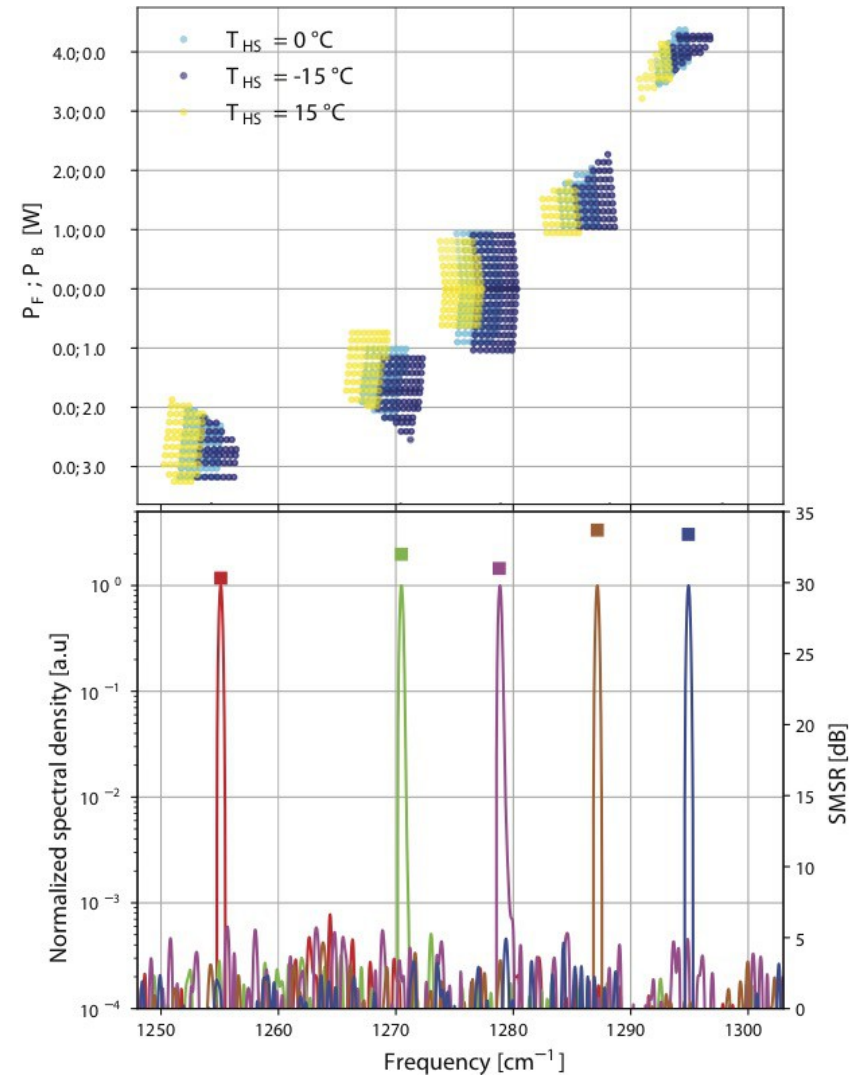
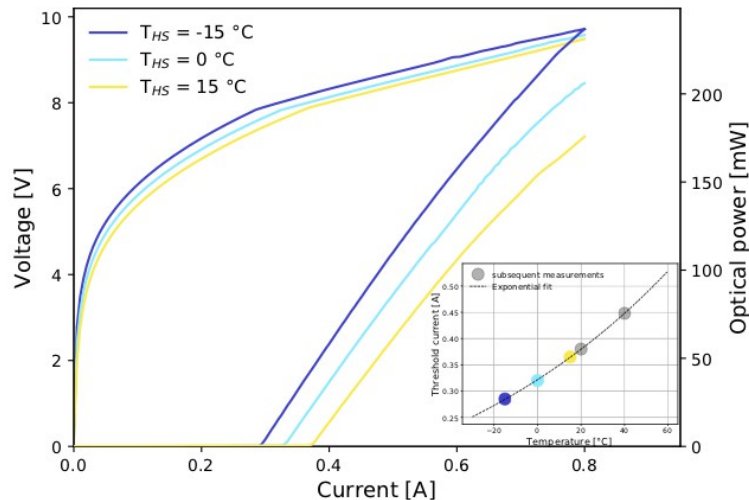
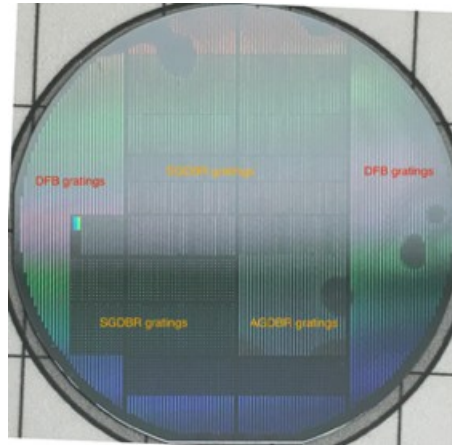




- Goals:
 - Number of clusters limited to 3-5
 - Wider gaps between clusters
 - Non-equidistant gaps
- Back and front DBR designed numerically by simulated annealing, inspired from metallurgy (AG)
- Etching profiles optimized considering the technological limitations (minimal structure size)
- Target frequencies selected for specific applications which can be non-equidistant on the contrary to first generation (SG)
- 2nd generation: AG and SG on same wafer



- Design: limited to 3- 5 clusters with broader gaps
- Very high CW power (> 200mW)
- 5 clusters lasers (AG)
 - Gaps up to $>10\text{cm}^{-1}$
 - Same amplitude for all reflectivity peaks
 - Very stable in clusters



- **Aim** of the **WaterSpy** team: to develop a device that will require a couple of hours for a full water sample analysis of **100 mL**, in search for three heterotrophic bacterial cells (*E.coli*, *Salmonella* and *P.aerruginosa*).



Escherichia coli

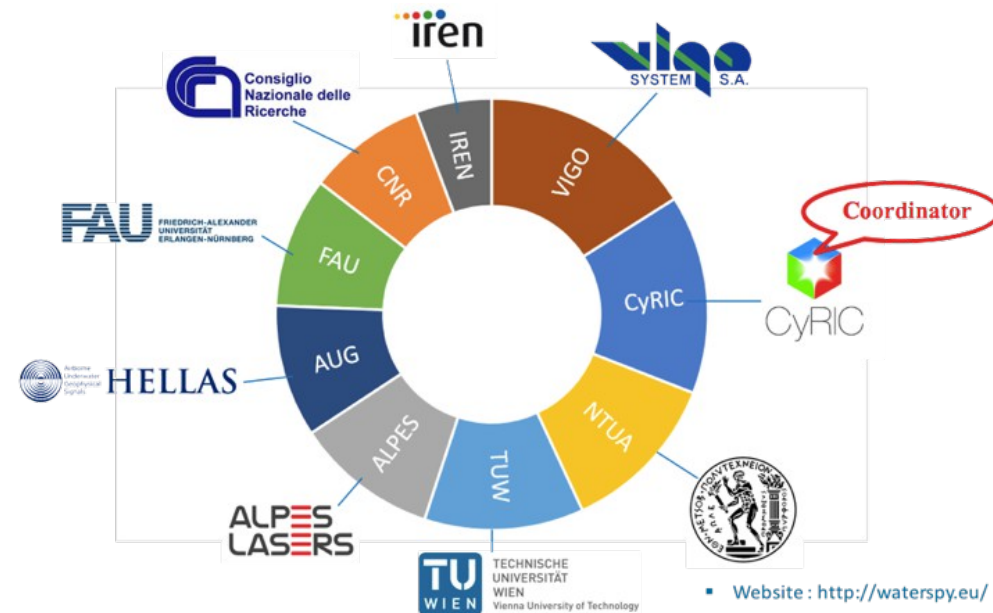


Salmonella enterica



Pseudomonas aeruginosa

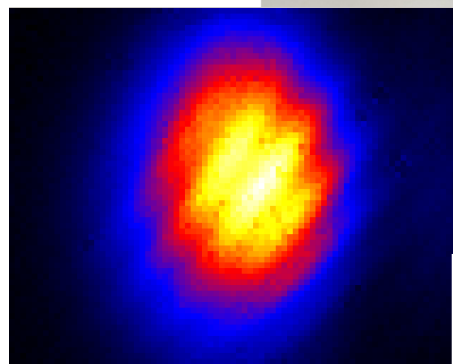
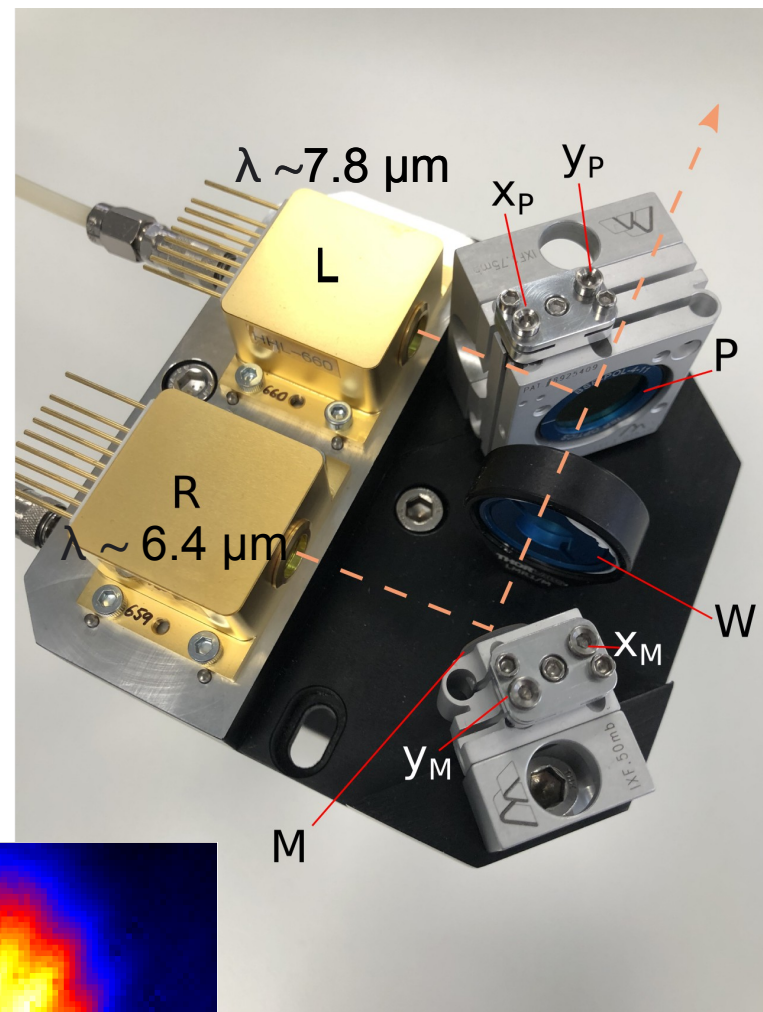
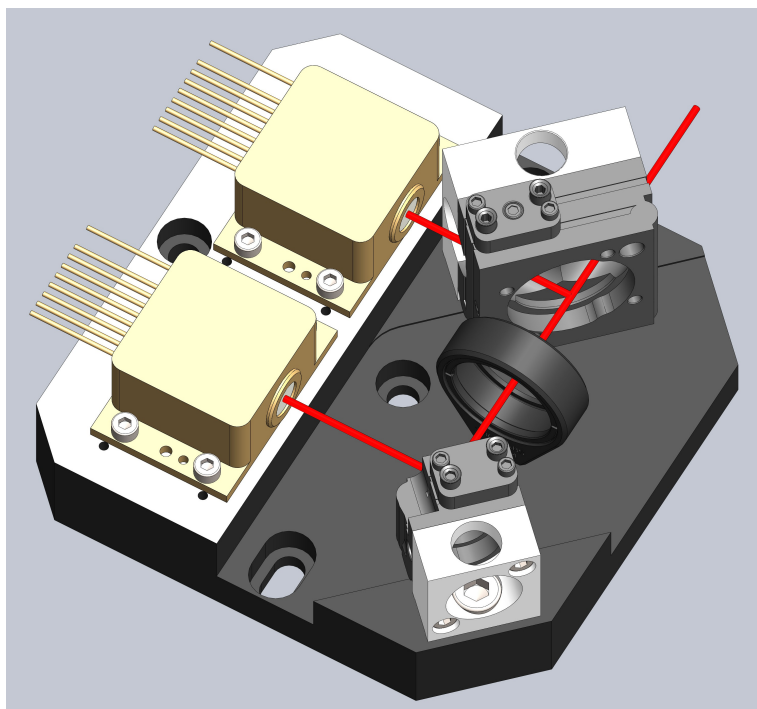
- In line with the EC and national regulations that require that no bacteria should be present in a sample of 100 mL of drinkable water.
- WaterSpy is taking advantage of advances in cutting edge photonic devices, in order to provide new capabilities in water analysis.



QC-XT 2nd generation

Beam combining


- Beam combining using
 - mirror (M)
 - half-wave plate (W)
 - polarizer (P)
- Good beam quality at the exit (FF at 1m)



The research leading to these results has received funding from European Union's Horizon 2020 research and innovation programmes:

- under grant agreement No 731778



- under grant agreement No 688265: **MIRPHAB** 

These projects are an initiative of the Photonics Public Private Partnership (www.photonics21.org).





Thank You



Visit:

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info@alpeslasers.ch
www.alpeslasers.ch



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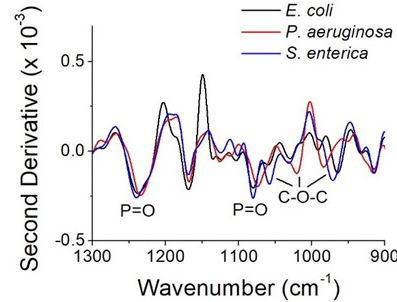
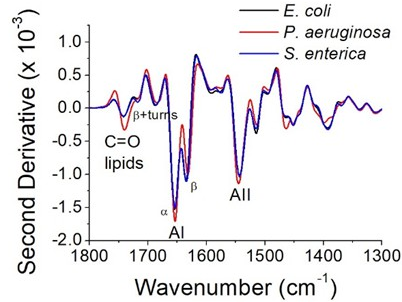
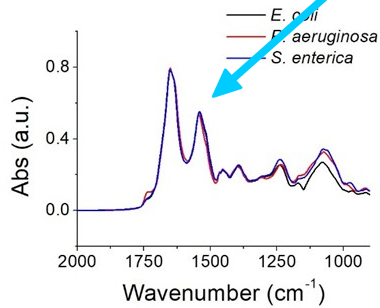
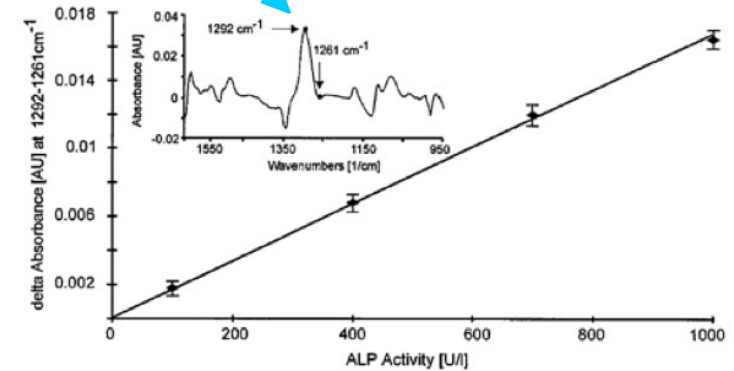
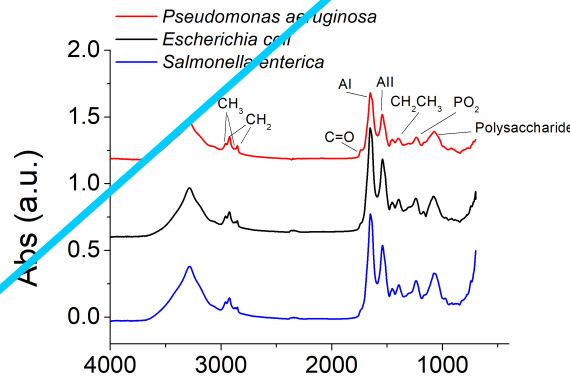
www.linkedin.com/

Bacteria could be identified through their **FT-IR bands**.

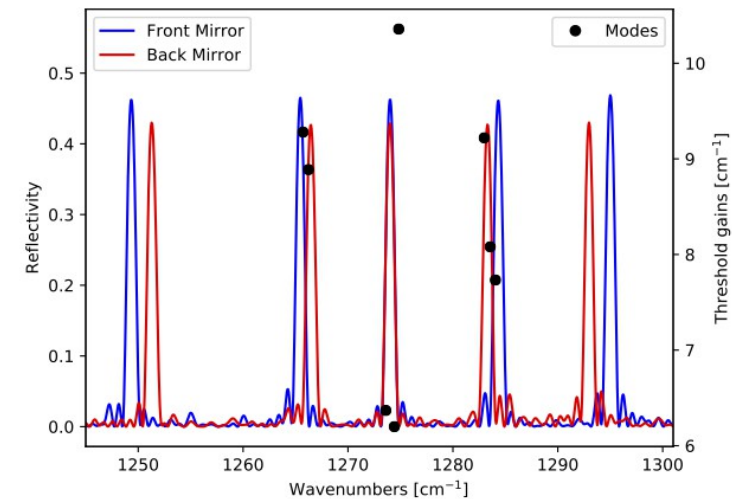
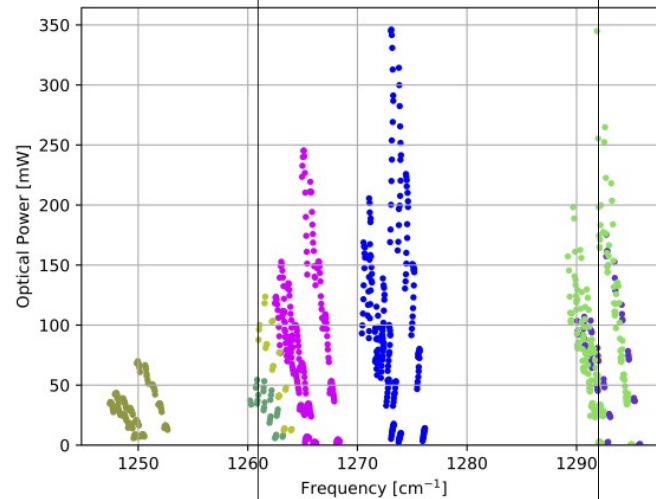
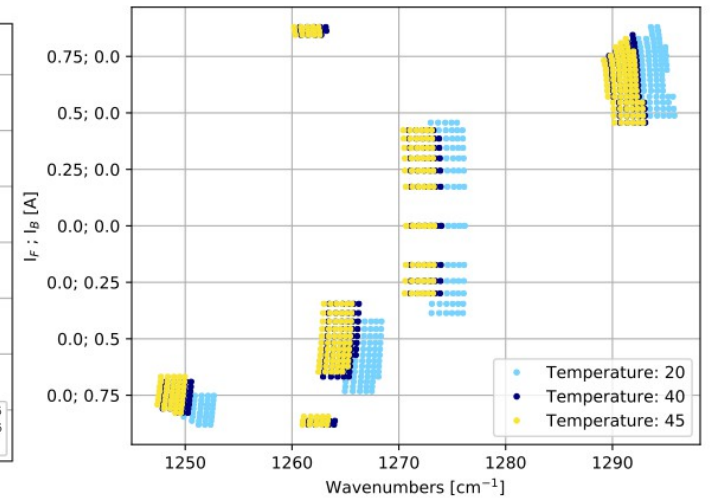
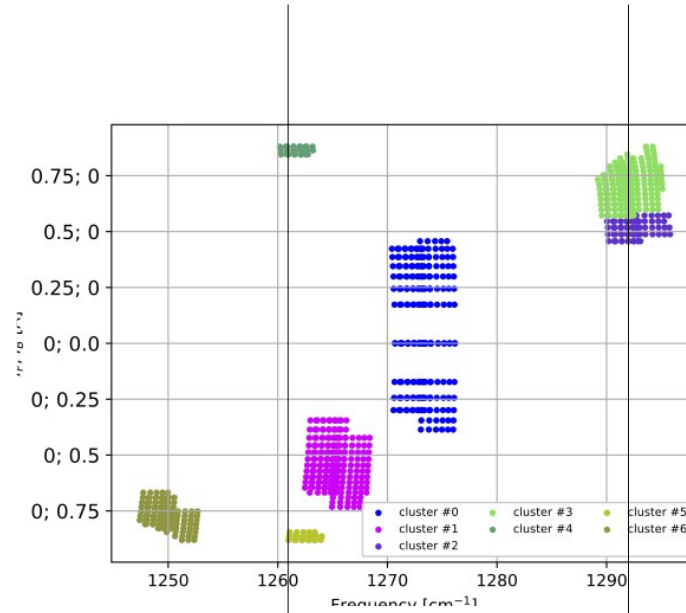


Two lasers to be fabricated:

- 1) Laser for amide II band around 1560cm^{-1}
- 2) Laser for catalytic reaction at $1261\text{cm}^{-1} + 1292\text{cm}^{-1}$



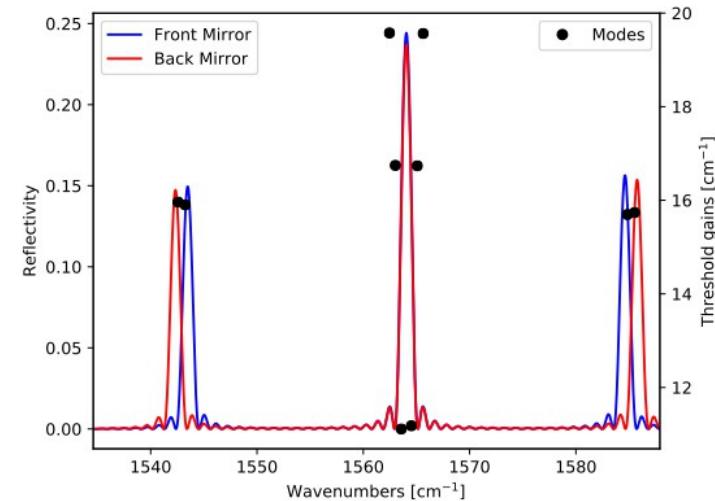
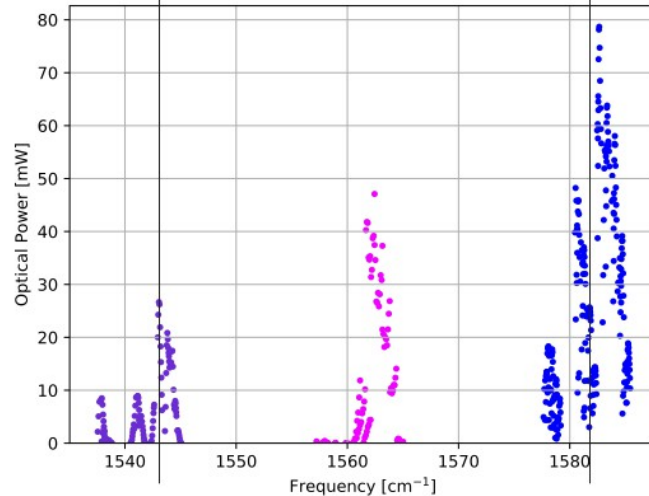
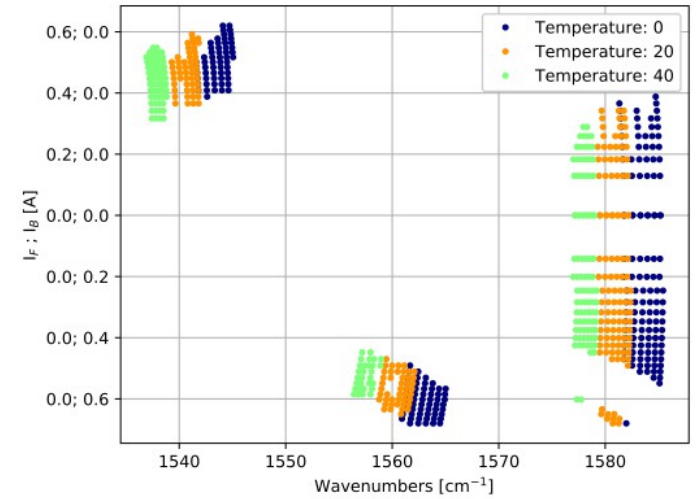
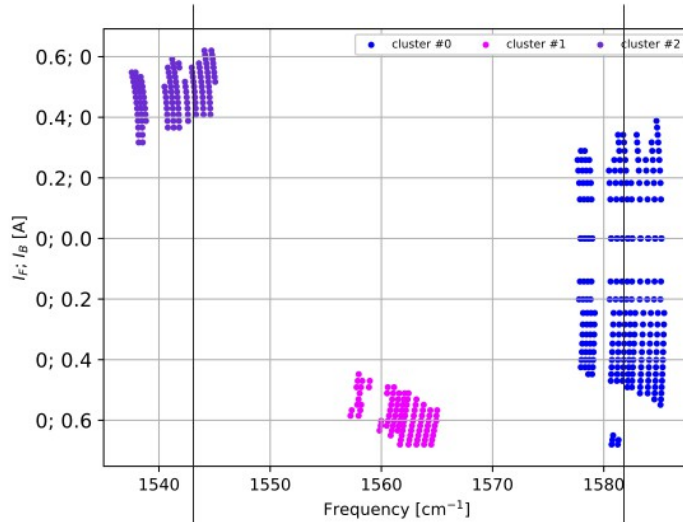
- WaterSpy needs
 - 1261cm⁻¹
 - 1292cm⁻¹
- Packaged laser (HHL)
- Both λ reached at 40-45C (same temperature important)
- 5 clusters laser (AG)
 - Good correlation with design
 - 1 cluster is missing



Cluster	I_B [A]	V_B [V]	I_F [A]	V_F [V]	I_L [A]	V_L [V]	Freq [cm ⁻¹]	T [C]	P_{opt} [mW]
#0-Back	0.00 - 0.44	0.0 - 1.7	0	0	0.36 - 0.80	7.9 - 9.7	1270.9 - 1278.0	0 - 50	211
#0-Front	0	0	0.00 - 0.40	0.0 - 1.6	0.36 - 0.80	7.9 - 9.7	1270.8 - 1278.0	0 - 50	168
#1-Front	0	0	0.40 - 0.60	1.6 - 2.2	0.36 - 0.80	7.8 - 9.5	1290.5 - 1297.7	0 - 50	121
#2-Front	0	0	0.51 - 0.88	2.0 - 3.5	0.47 - 0.80	8.0 - 9.4	1289.4 - 1296.4	0 - 50	181
#3-Back	0.36 - 0.76	1.4 - 3.2	0	0	0.36 - 0.80	7.7 - 9.5	1262.8 - 1270.1	0 - 50	170
#4-Back	0.80 - 0.88	3.7 - 4.1	0	0	0.59 - 0.80	8.2 - 9.0	1261.1 - 1263.3	40 - 50	56
#4-Front	0	0	0.76 - 0.88	3.3 - 3.9	0.54 - 0.80	8.1 - 9.1	1260.4 - 1264.7	20 - 50	55
#5-Back	0.62 - 0.88	2.7 - 3.8	0	0	0.47 - 0.80	8.0 - 9.3	1247.6 - 1254.2	0 - 50	73

Table 1: Overview of the clusters.

- WaterSpy needs: ~1545 + 1580cm⁻¹ (broad feature)
- Both λ reached at 0-40C
- 3 clusters laser (SG)
 - Very good correlation with design
 - Gap ~ 21cm⁻¹

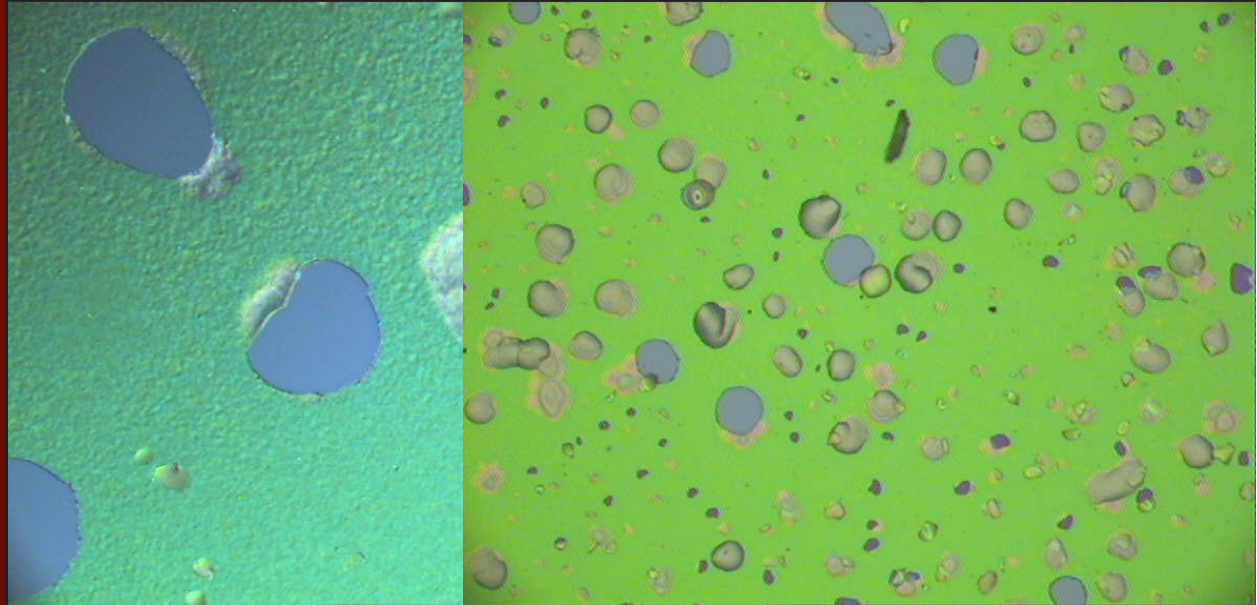


Cluster	I_B [A]	V_B [V]	I_F [A]	V_F [V]	I_L [A]	V_L [V]	Freq [cm ⁻¹]	T [C]	P_{opt} [mW]
#0-Back	0.00 - 0.68	0.0 - 3.1	0	0	0.36 - 0.54	10.8 - 12.5	1577.8 - 1585.4	0 - 40	79
#0-Front	0	0	0.00 - 0.39	0.0 - 1.6	0.36 - 0.54	11.0 - 12.5	1577.6 - 1585.2	0 - 40	65
#1-Back	0.45 - 0.68	2.0 - 3.0	0	0	0.36 - 0.54	10.6 - 12.1	1557.2 - 1565.0	0 - 40	47
#2-Front	0	0	0.32 - 0.62	1.3 - 2.6	0.36 - 0.54	10.7 - 12.2	1537.6 - 1545.1	0 - 40	27

Table 1: Overview of the clusters.

Ruggedized packaging

HP-QCL





Ruggedized packaging development

Ruggedized packaging

Design:

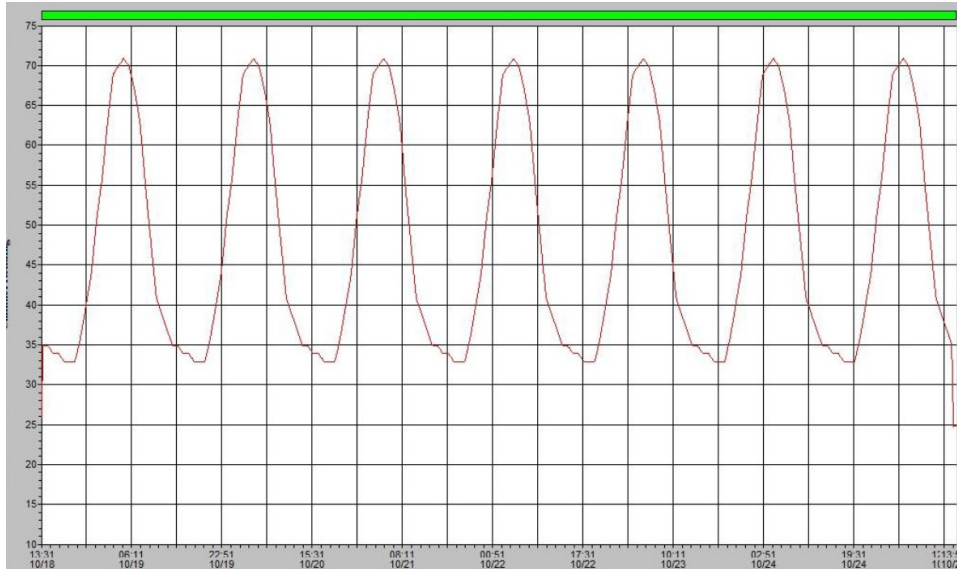
- Numerical simulations of environmental conditions using finite element method (laser package + driver)
- Calculation of safety margins

Experimental validation:

- Proof of design with a set of 6 lasers + 6 drivers:
 - 4x MW QCLs: 1 W average at 4.0 μm
 - 2x LW QCLs: 1 W average at 9.7 μm

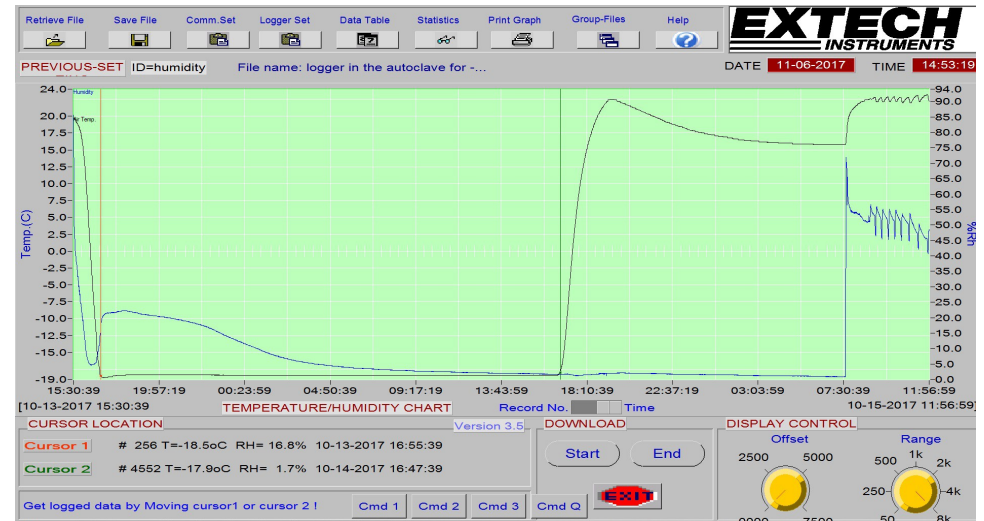
Temperature cycle tests

Ruggedized packaging



High temperature cycles:

- 7 cycles of 24h up to 71°C
- Per MIL-STD 810F, method 501.4, Procedure I

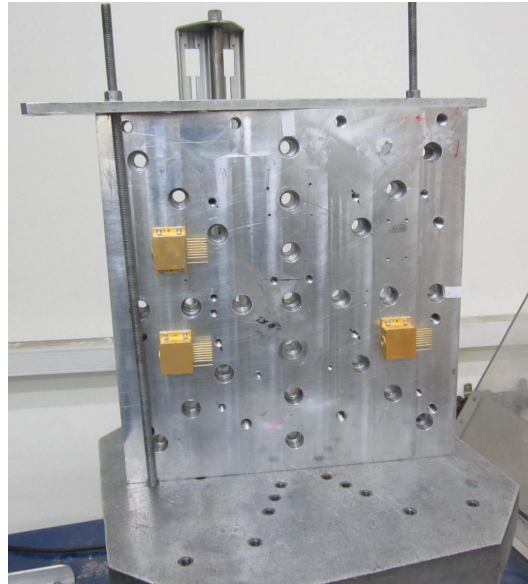
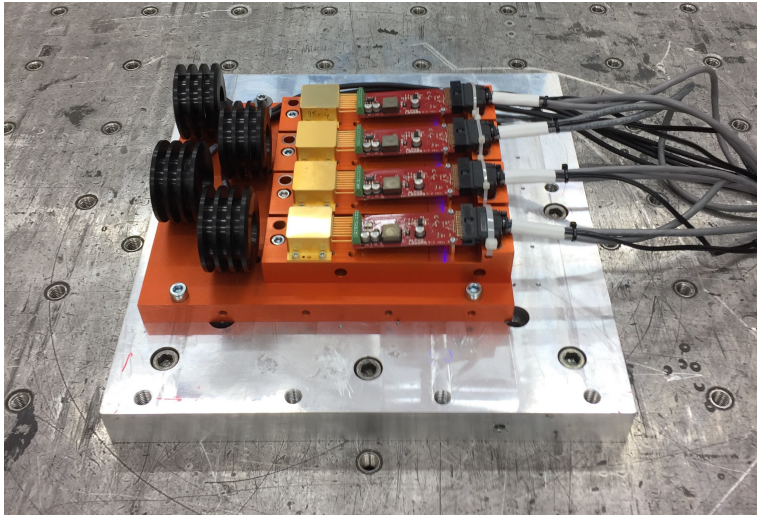


Low temperature cycles:

- 1 cycle of 24h down to -20°C
- Per MIL-STD 810F, method 502.4, Procedure I

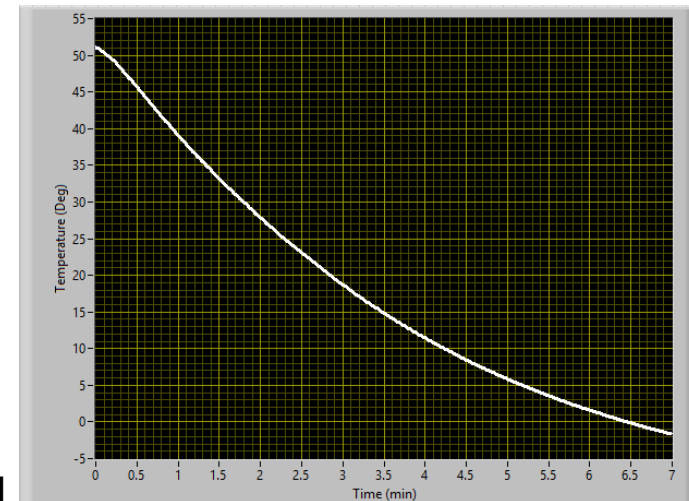
Vibration / shock tests

Ruggedized packaging



Temperature shock tests:

- Per MIL-STD 810F, Method 503.4, procedure II
- Cooling down from 55°C to 0°C at a rate of $\geq 11^\circ\text{C}/\text{min}$



Vibration tests:

- Per MIL-STD 810F, Figure 514.5C-17
- $0.04 \text{ g}^2/\text{Hz}$ from 20 Hz to 1 kHz
- 1 hour per axis

Shock tests:

- Per MIL-STD 810F, Method 516.5, procedure I
- Half sine, 85 g, 5 ms
- 3 axes, 6 shocks per axis



Ruggedized packaging specifications

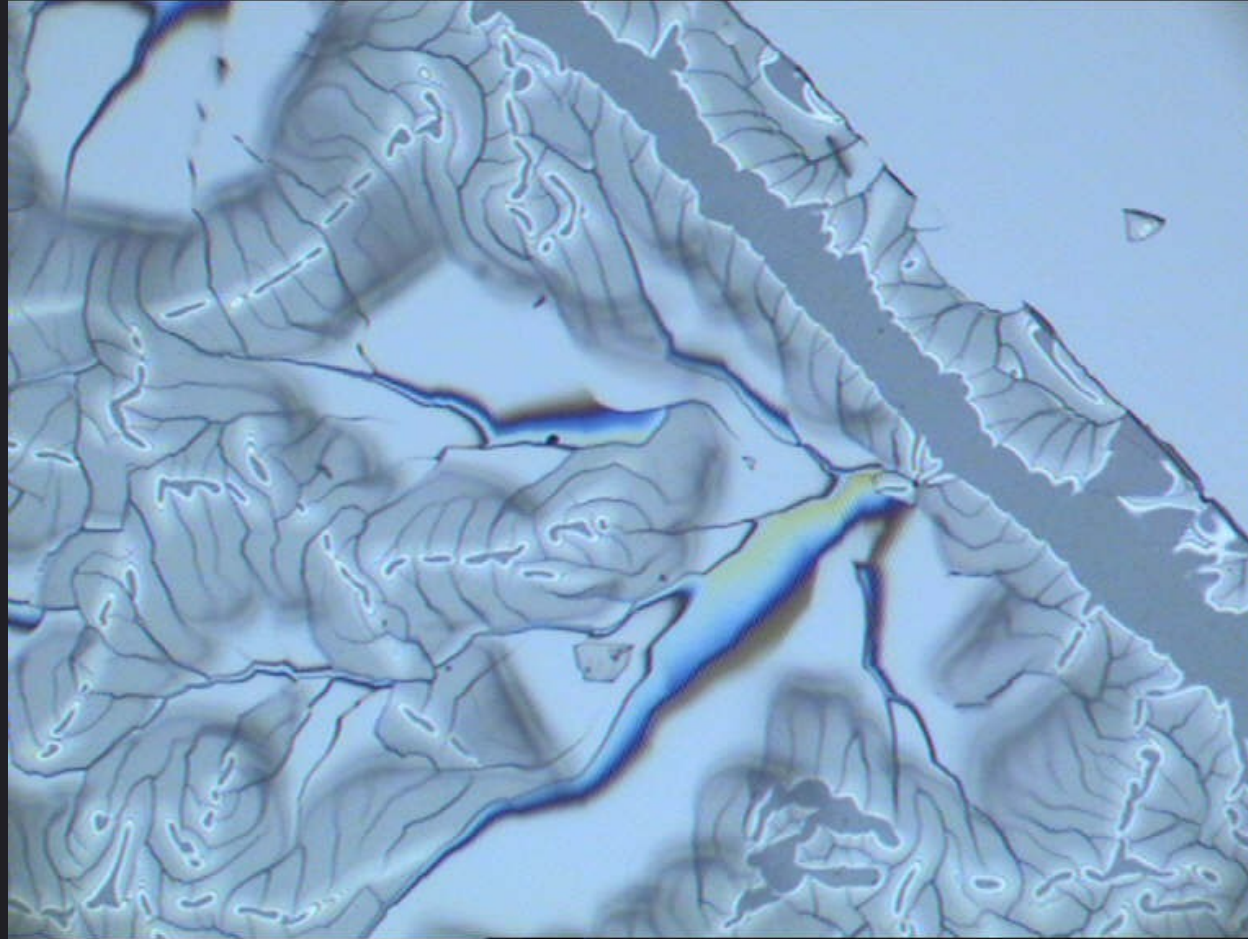
Proof of design results

- Beam pointing and divergence:
 - ✓ Beam pointing precision and retention: ± 0.5 mrad
 - ✓ Beam divergence precision and retention: $\pm 10\%$ of divergence
 - Environmental conditions:
 - ✓ Internal temperature (operating): 0°C to 25°C
 - ✓ Heatsink temperature (operating): 0°C to 35°C
 - ✓ Ambient temperature* (operating): -20°C to $+71^{\circ}\text{C}$
 - ✓ Storage temperature (non-operating): -20°C to $+71^{\circ}\text{C}$
 - ✓ Thermal shock: $+55^{\circ}\text{C}$ to 0°C , rate = 11°C
 - ✓ Vibrations: $0.04\text{ g}^2/\text{Hz}$, from 20 Hz to 2 kHz, 1 hour per axis
 - ✓ Mechanical shocks: 85 g, 5 ms, half-sine profile, 6 shocks per axis
- Met for the packaged laser and electronics driver

*Air temperature with laser mounted on heatsink

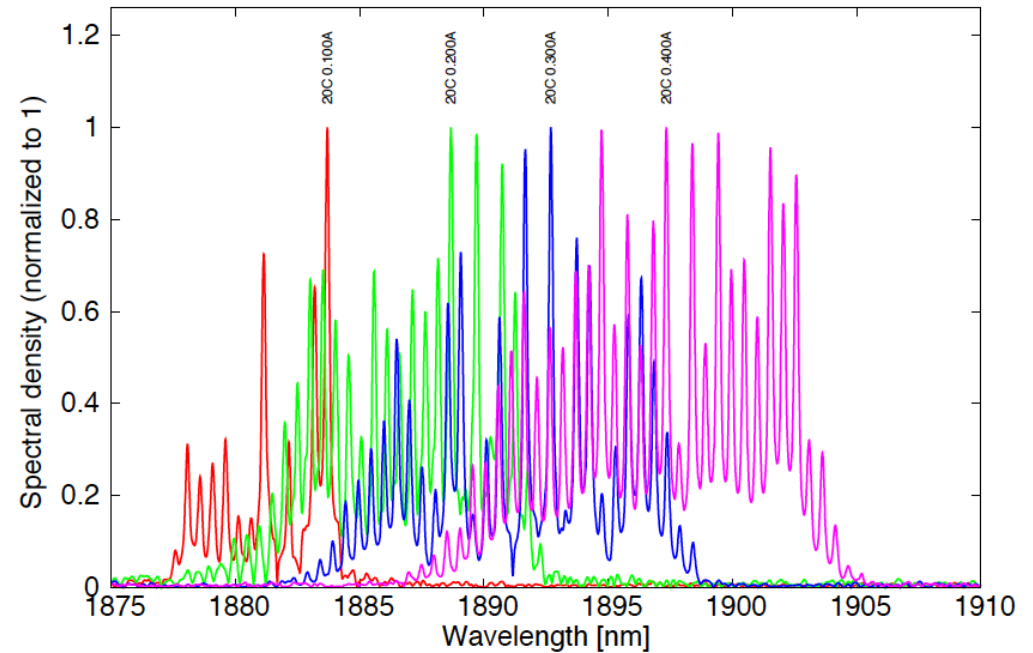
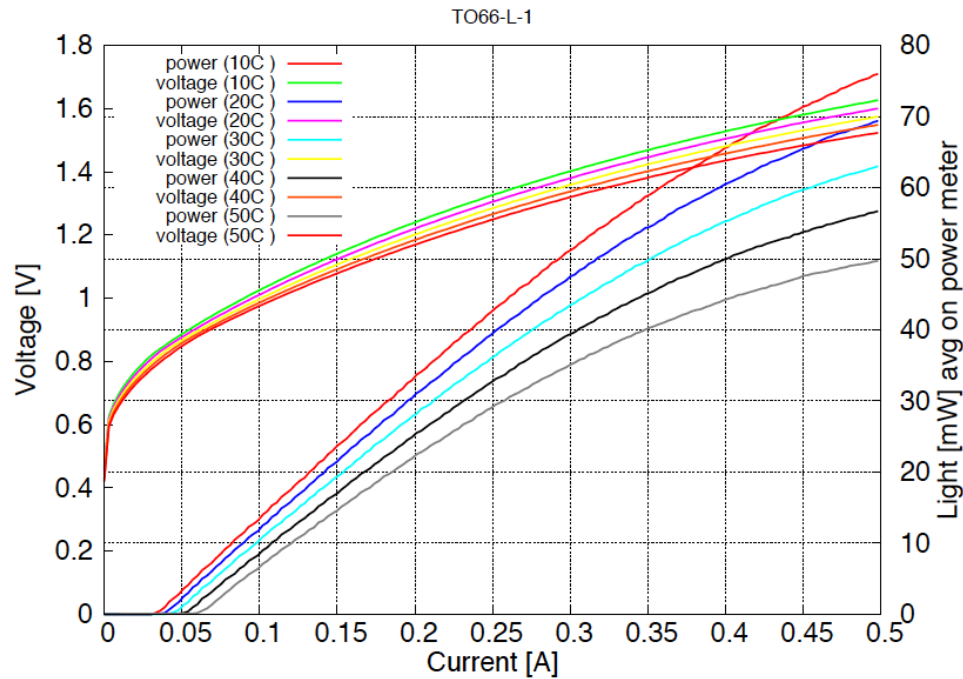
NEW: SWIR diode lasers

FP-LD

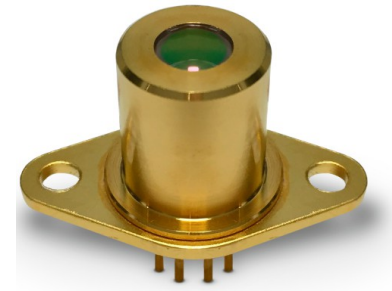


Short-wave infrared InP diode lasers

Laser performances



- Continuous-wave operation in TO66 package
- $T = 10^{\circ}\text{C} - 50^{\circ}\text{C}$
- $P > 50\text{mW}$
- Wavelength = $1.89 \mu\text{m}$
- Laser: 1mm-long / $4 \mu\text{m}$ -wide



Short-wave infrared InP diode lasers

Laser performances

Central Wavelength	Max. Power
1450 nm	30 mW
1470 nm	50 mW
1550 nm	30 mW
1630 nm	50 mW
1650 nm	50 mW
1730 nm	30 mW
1740 nm	40 mW
1830 nm	50 mW
1890 nm	50 mW
2080 nm	20 mW
2100 nm	10 mW
2150 nm	50 mW

- 12 different wavelengths between 1.45 μm and 2.15 μm available
- Mature InP-based technology